



SERMA TECHNOLOGIES

Serma Group

Comparison between SnPb63/37 - SAC305 solder:

Structure and intermetallics morphologies
after thermal stress on PCB – ENIG finishing

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Introduction

- SERMA TECHNOLOGIES
- Objectives

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Experimental Procedure

- Taguchi Plan
- Samples and test description

3

Results and discussion

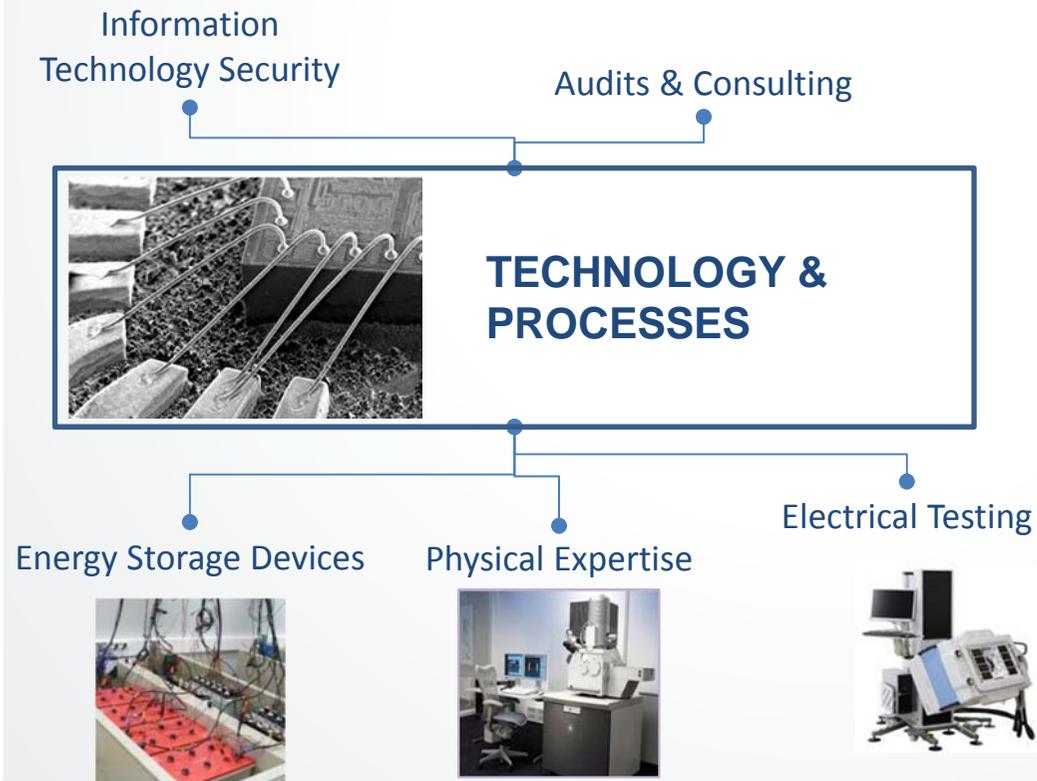
- Parameters effects on IMC size
- IMCs Morphologies inspection

4

Conclusion & Next Steps

The most important independent electronic laboratory in Europe

- > **20 years of experience - multi-sectoral**
- > **6 000 analyzes / year**



- Construction analysis
- Failure analysis
- Qualifications
- Characterizations

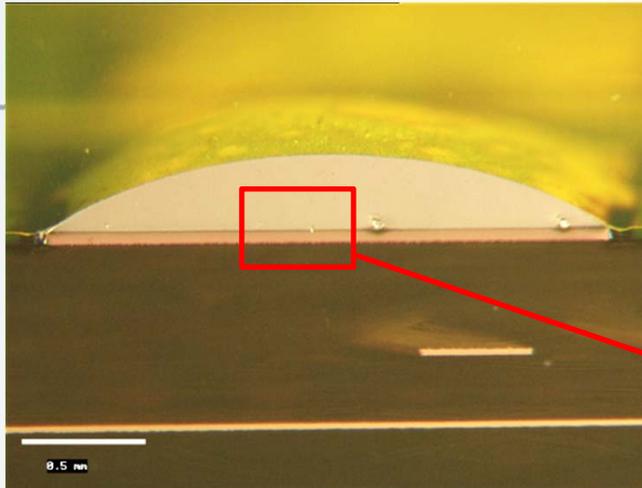
How to Explain:

- *The low occurrence of cracking at PCB/Solder interface on SAC305 solders?*
- *That IMC with SAC solder are thicker than IMC with SnPb solder, for a same reliability level?*

Project Objectives:

- A better understanding of the IMCs observed in section especially during FA
 - link the observations to the structural causes
- Observe and assess the evolution of IMC morphologies according to different parameters (process and / or aging).
- Adapt new inspection methods for IMC inspection (more representative than the classical cross sectioned view)

REMINDERS

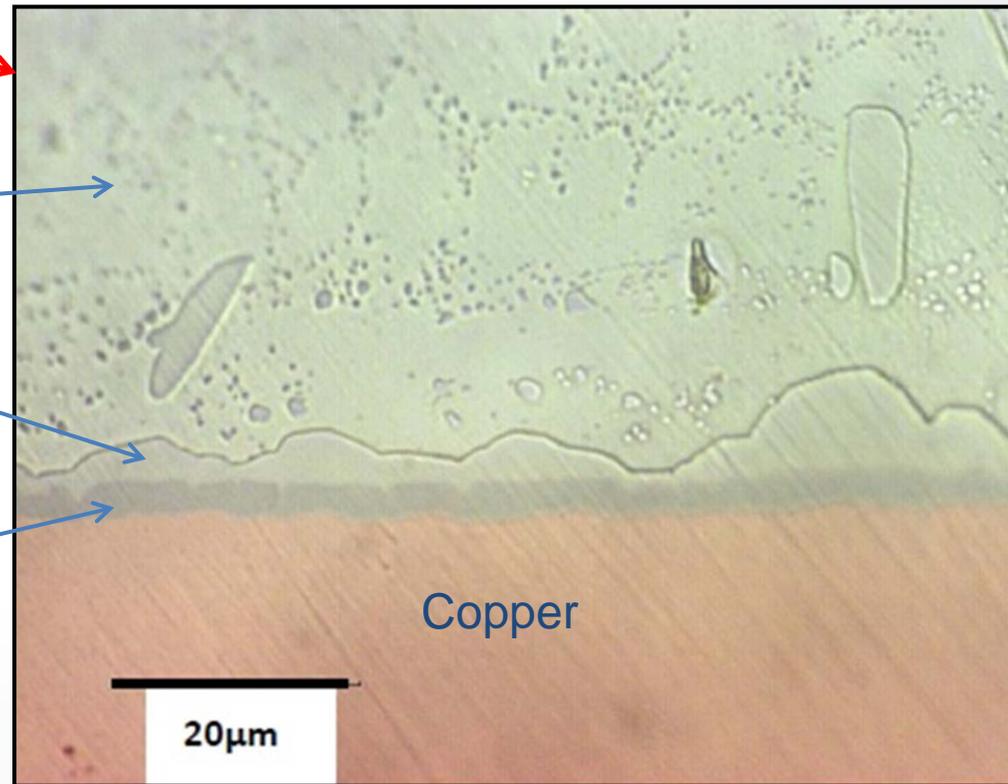


PCB ENIG (Au/NiP/Cu) – View in cross section

Solder
(SAC 305)

Intermetallics
Compounds (IMCs)
Type Sn/Ni

Nickel (ENIG
finishing)



Aim: Assess the effects and interactions between selected parameters (Process & Ageing) and their levels, on IMC size and morphologies

Solder type	SnPb 63/37*			SAC 305**		
Levels	#1	#2	#3	#1	#2	#3
Bath temperature (°C)	235	255	/	245	265	/
Time on the solder bath (s)	5	10	/	5	10	/
125°C Isothermal ageing time (h)	0	500	1000	0	500	1000

Parameters selected in function of the most common usage in the industry

* SnPb 63/37 (63%wt Sn; 37%wt Pb)

** SAC 305 (3%wt Ag; 0,5%wt Cu; Sn Basis)

Fixed parameters:

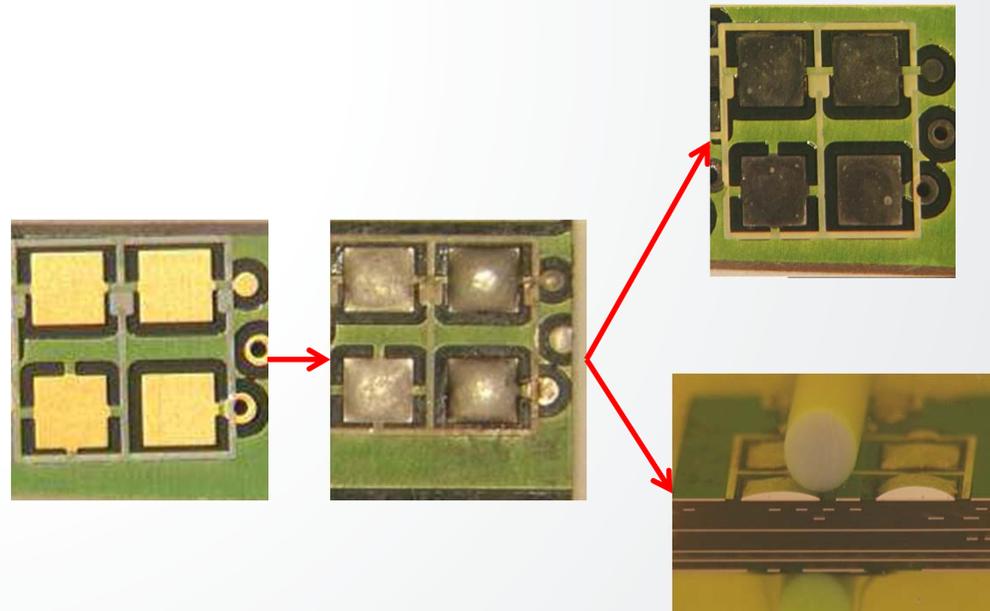
- Sample geometry: SMD Pads with ENIG Finishing (Au: 0,1 μ m – Ni: 4 μ m)
- No components assembled
- Soldering by floating method, time & temperature controlled by Menisco device (Métronelec).
- Flux: Type ROL 1

Inspection:

- SEM-EDX inspection
- 3 type of samples for 3 ways of inspection
 - Cross sectioned view
 - Revealed Cross sectioned view
 - Revealed aerial view

→ Size

→ Morphology



Cross section

Solder (SAC 305)

IMCs

NiP

Cu

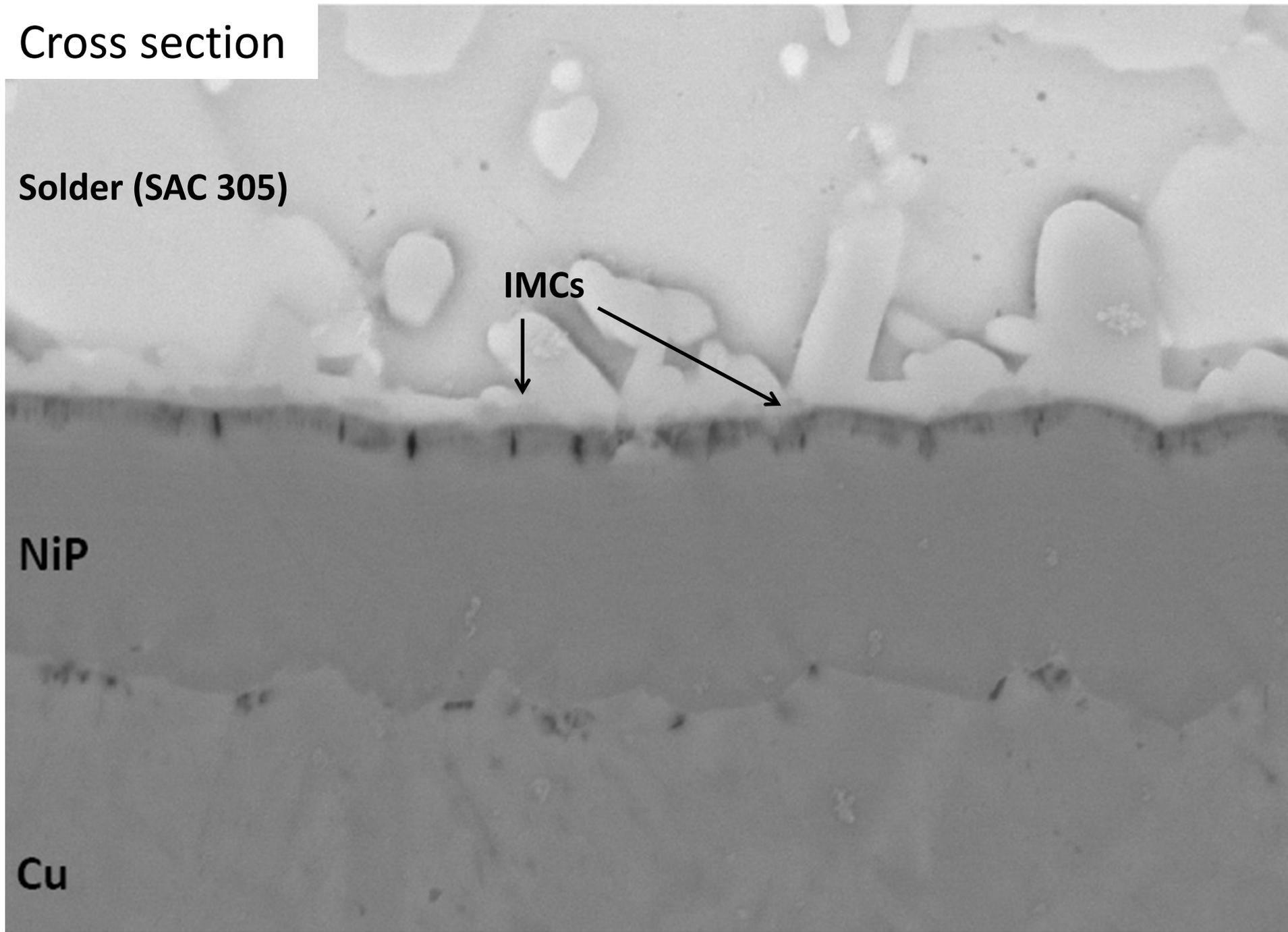
Mag = 6.00 K X

2 μ m

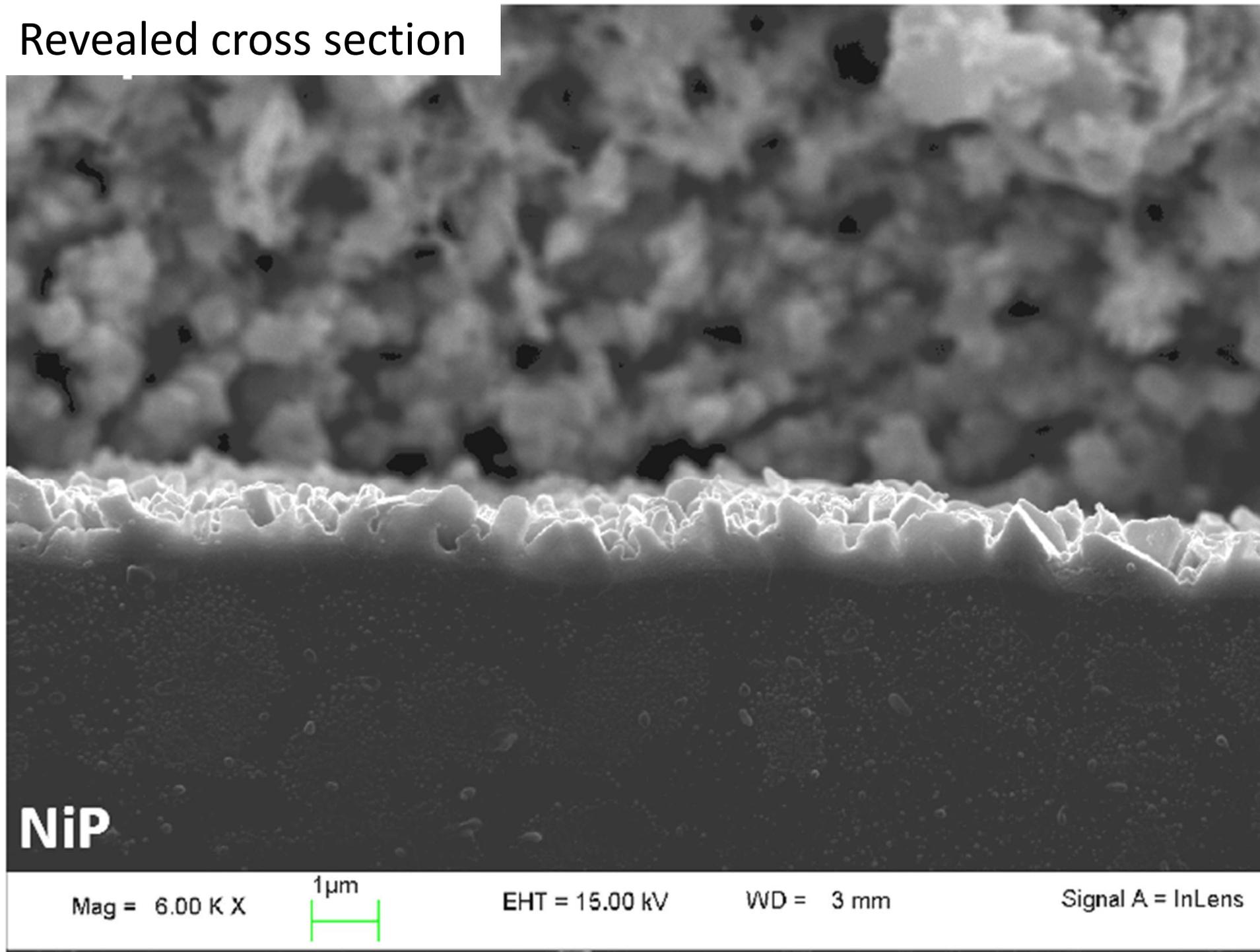
EHT = 20.00 kV

WD = 7.9 mm

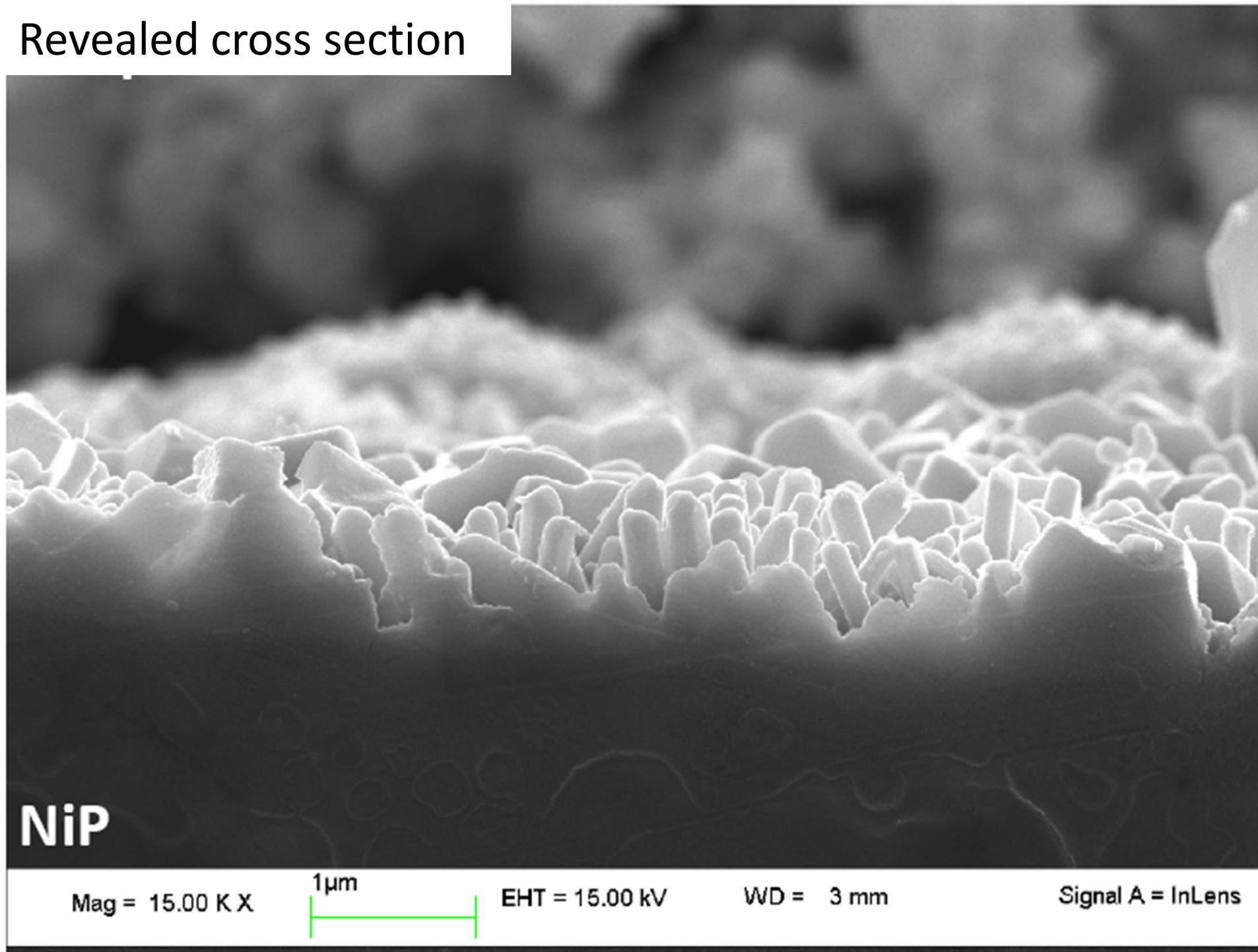
Signal A = BSD



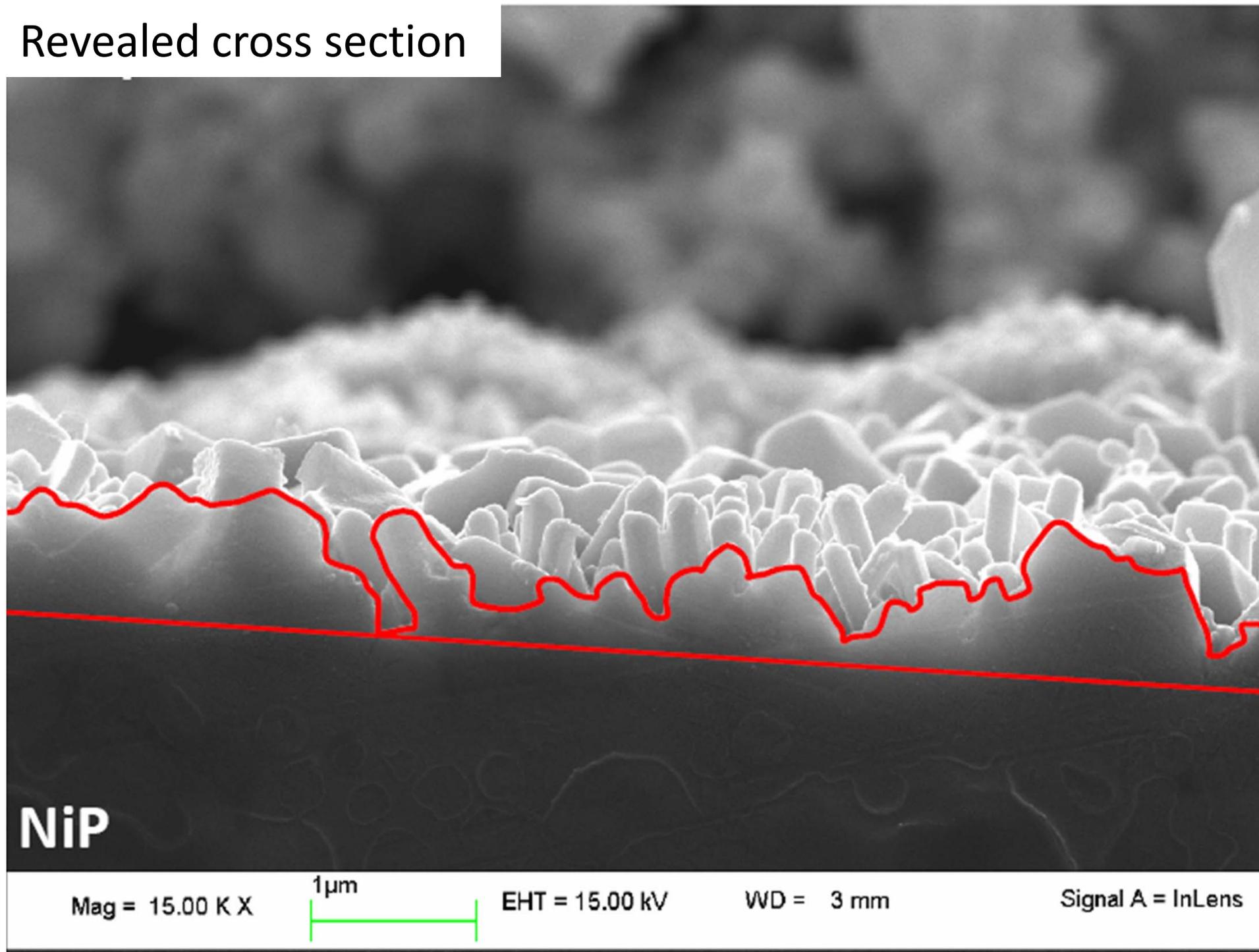
Revealed cross section



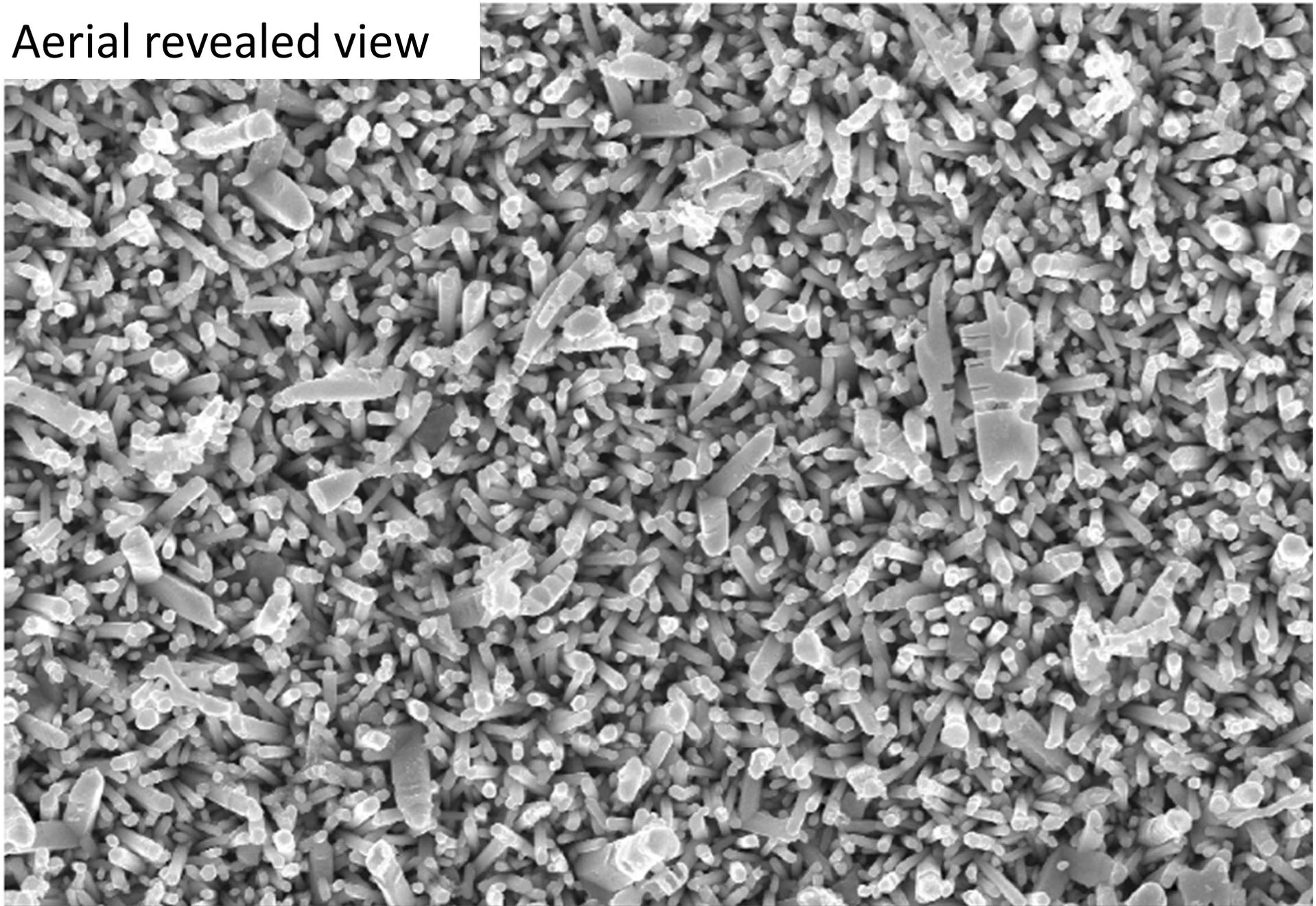
Revealed cross section



Revealed cross section



Aerial revealed view



Mag = 5.00 K X

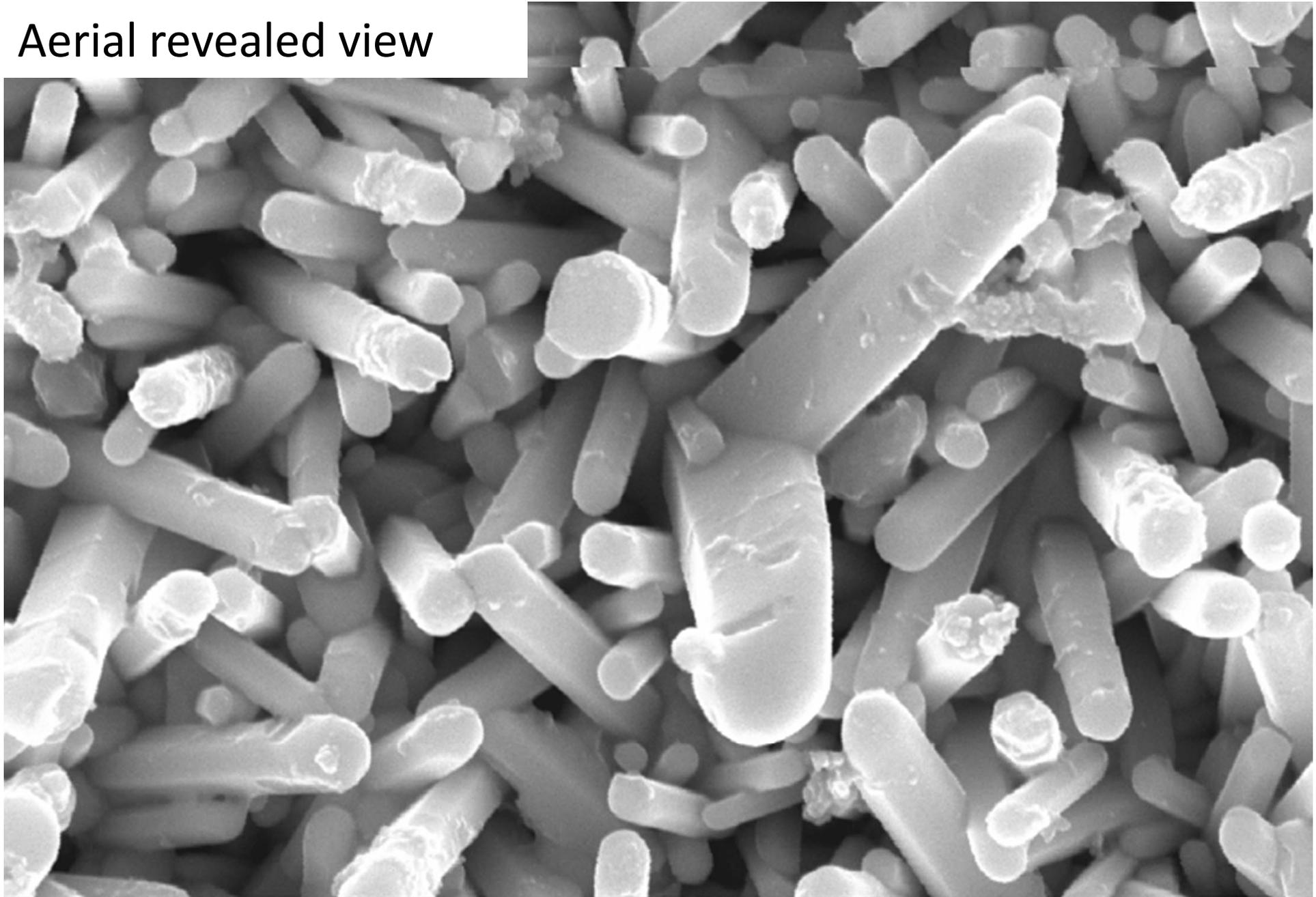


EHT = 15.00 kV

WD = 3 mm

Signal A = InLens

Aerial revealed view



Mag = 25.00 K X



EHT = 15.00 kV

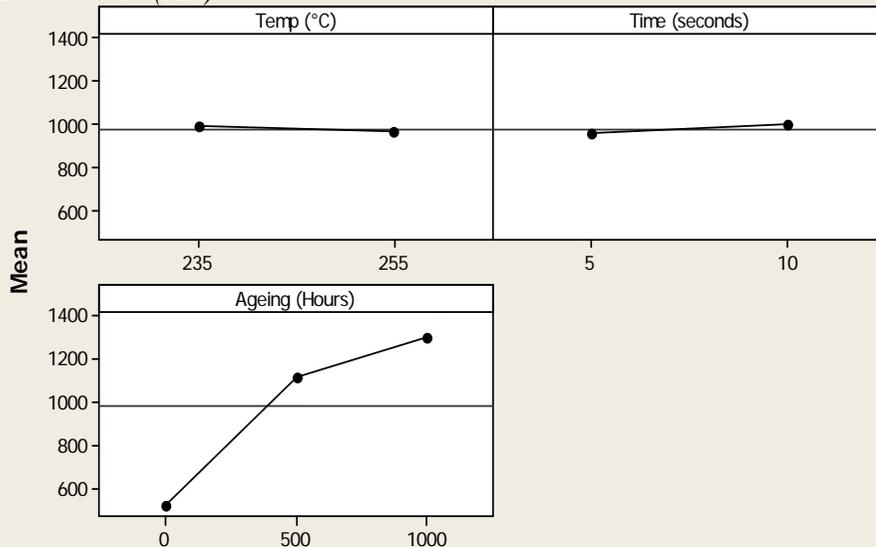
WD = 3 mm

Signal A = InLens

Effects of the 3 selected parameters

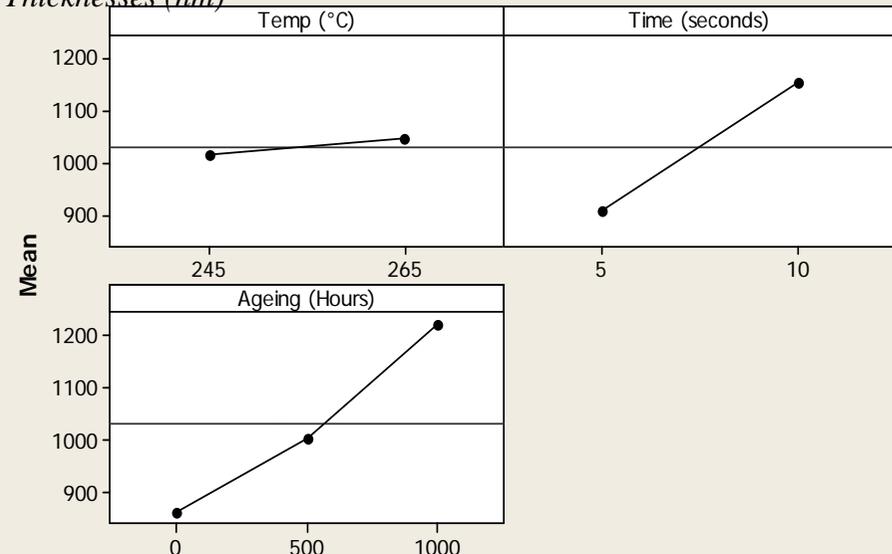
Avg of IMC
Thicknesses (nm)

SnPb 63/37 Bath



Avg of IMC
Thicknesses (nm)

SAC305 Bath



Each point = Average of de 20 measurements
Standard deviation ~ 100nm

125°C Isothermal Ageing Effect

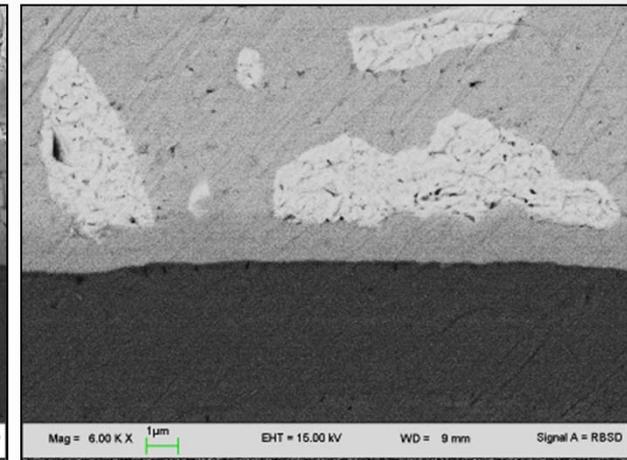
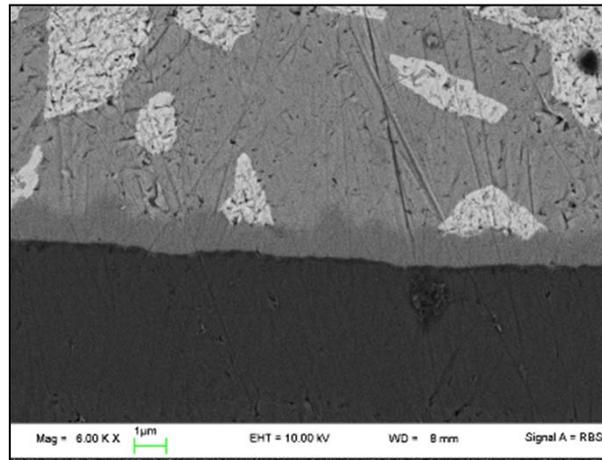
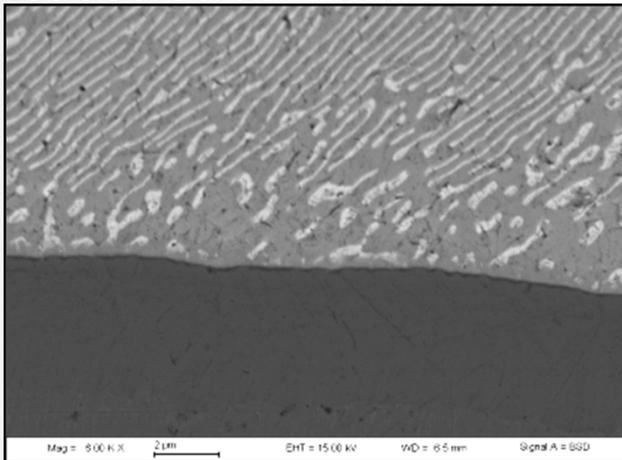
Cross sectioned views

0 Hour

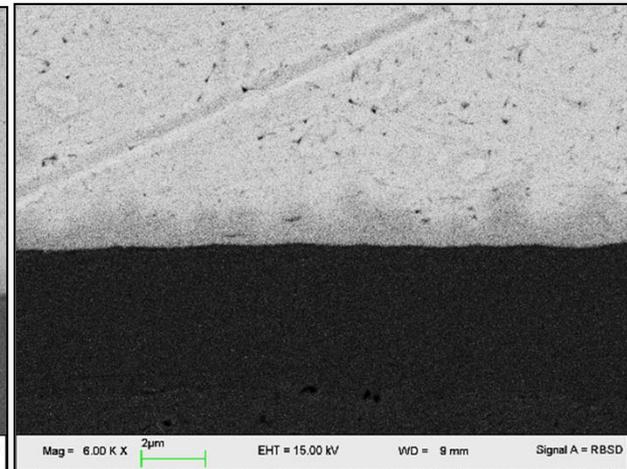
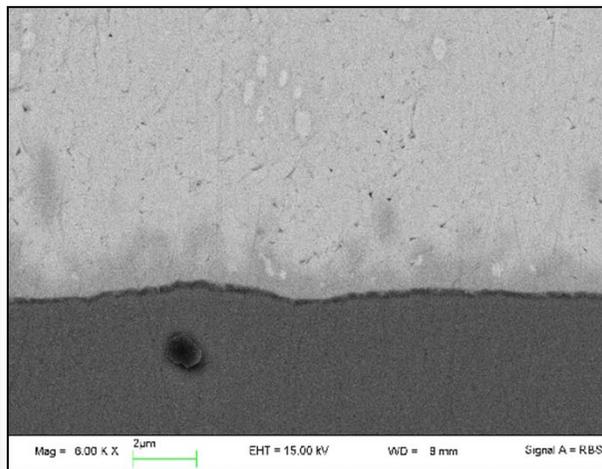
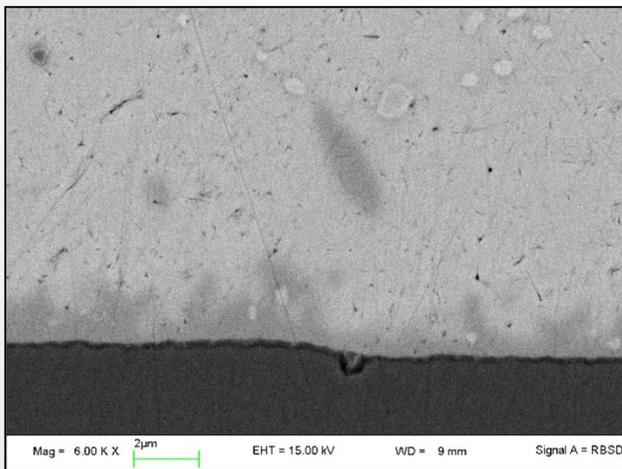
500 Hours

1000 Hours

Leaded solder Sn/Pb 63/37



Lead Free: SAC305



125°C Isothermal Ageing Effect

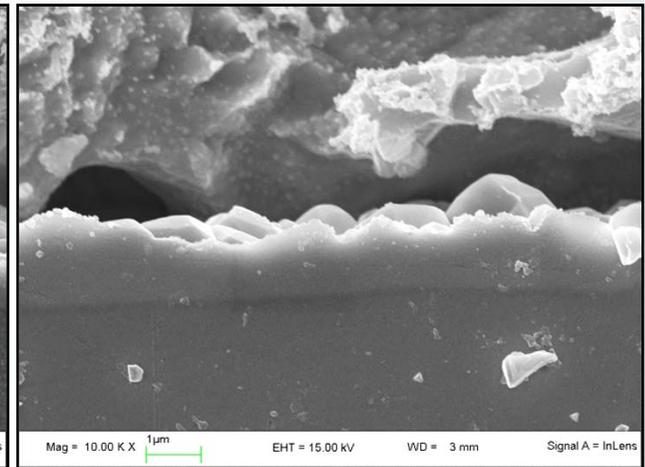
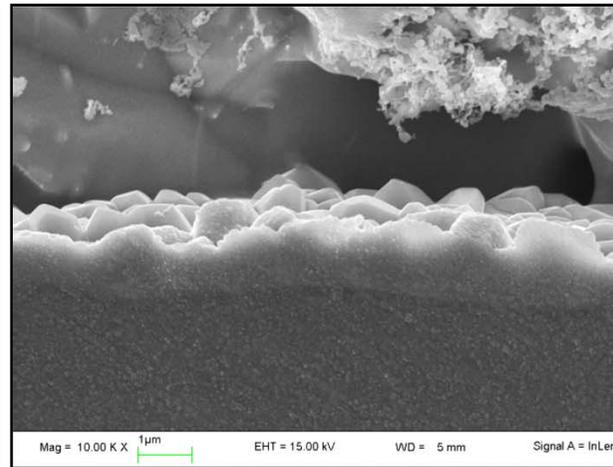
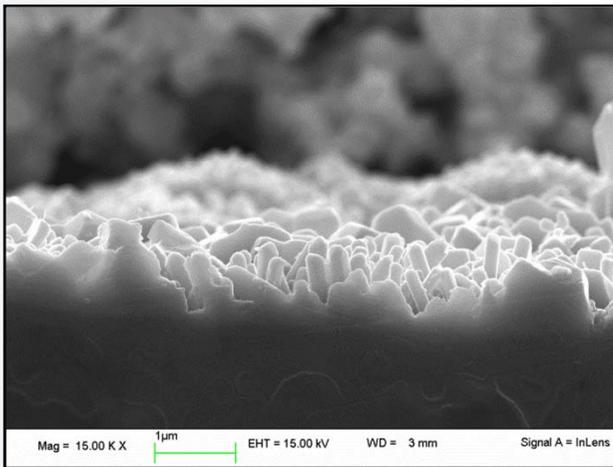
Revealed cross sections

0 Hour

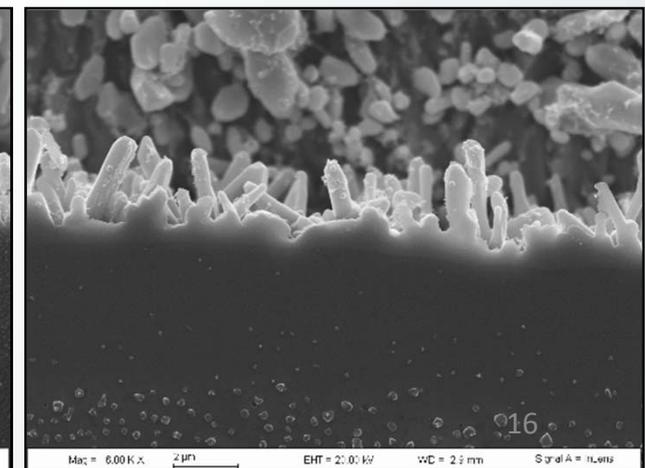
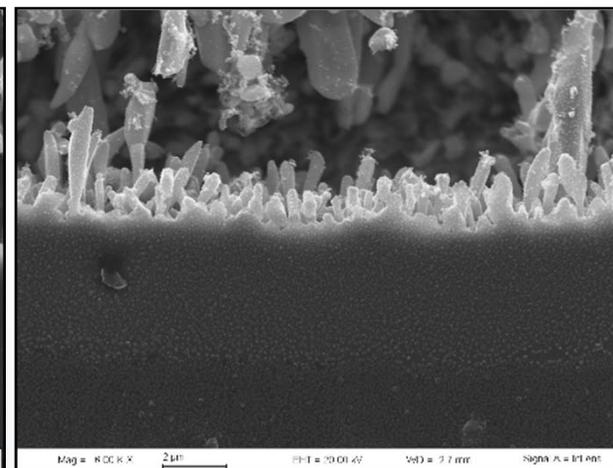
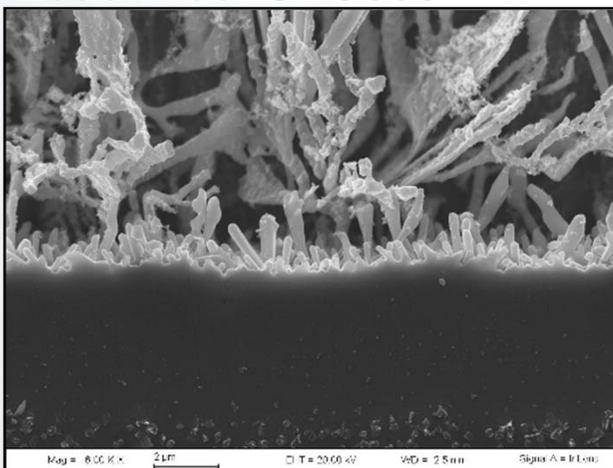
500 Hours

1000 Hours

Leaded solder Sn/Pb 63/37



Lead Free: SAC305



125°C Isothermal Ageing Effect

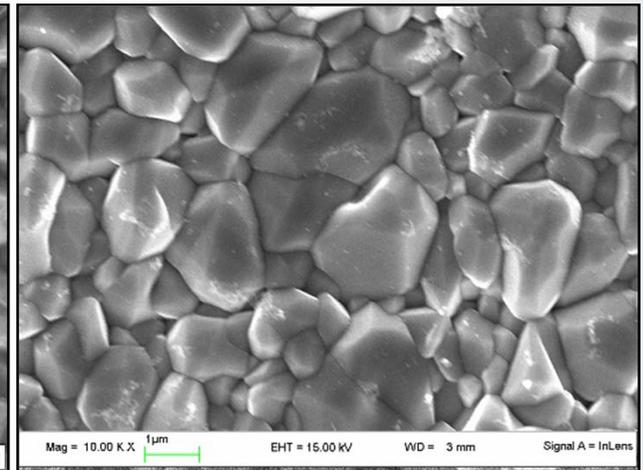
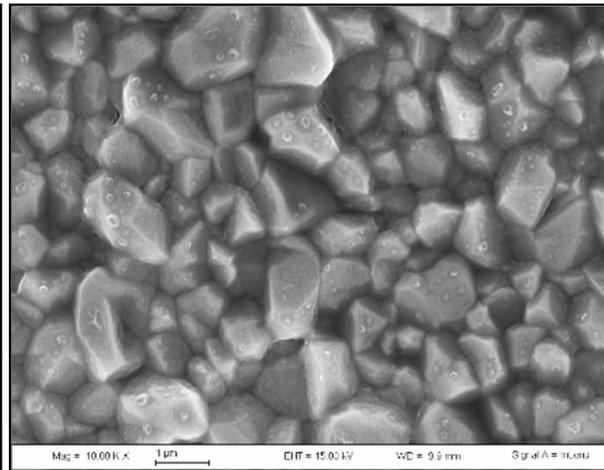
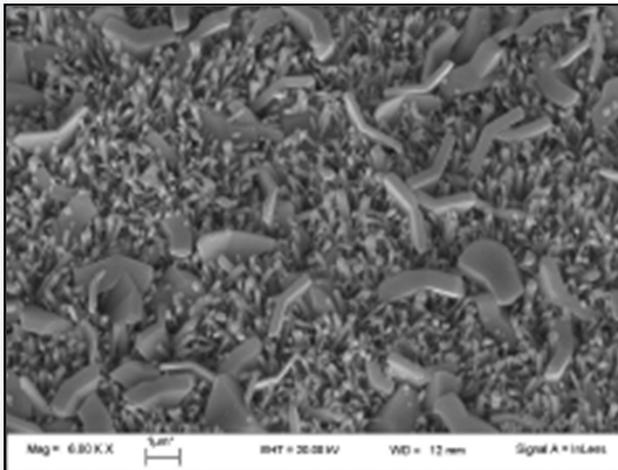
Aerial revealed views

0 Hour

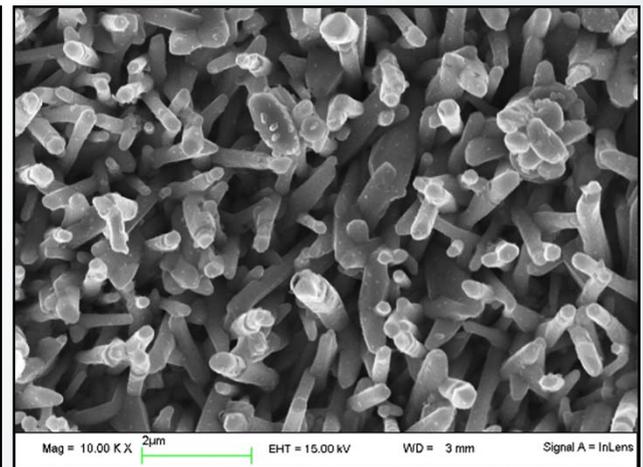
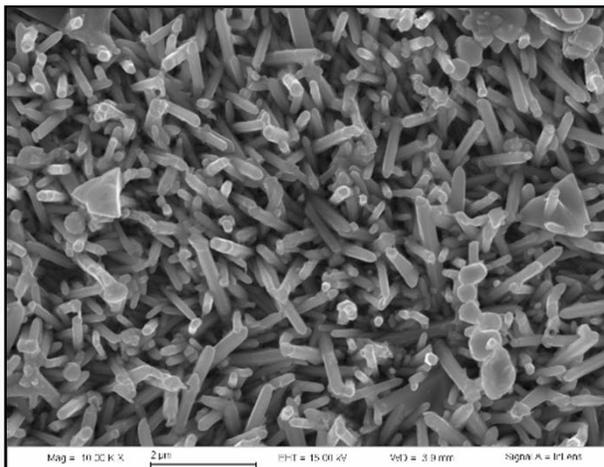
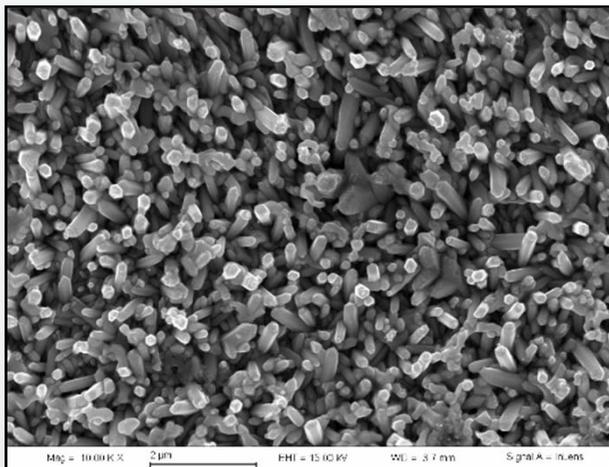
500 Hours

1000 Hours

Leaded solder Sn/Pb 63/37

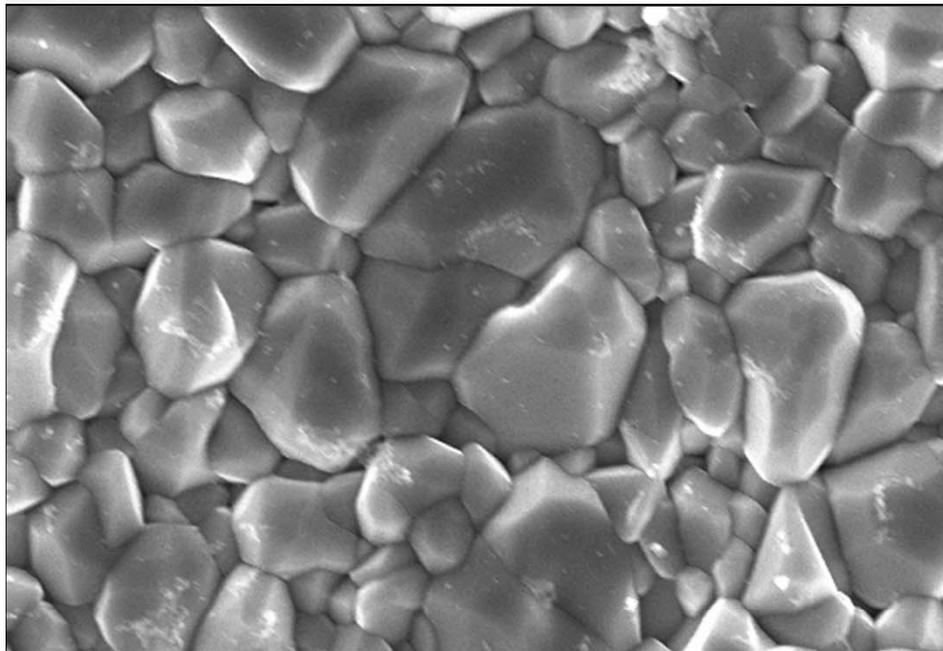


Lead Free: SAC305



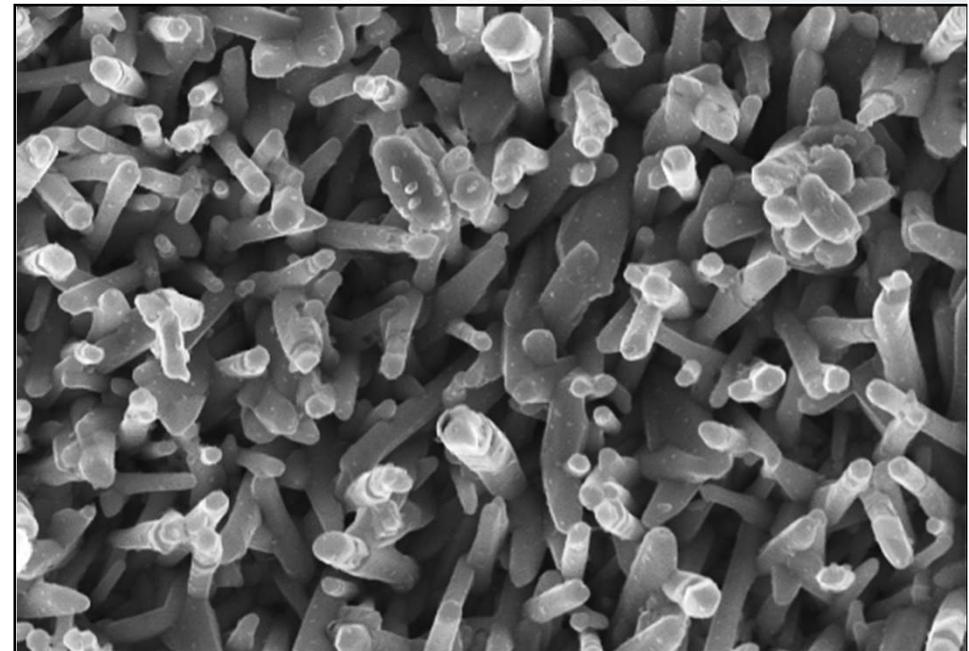
Aerial revealed views @ 1000h

Leaded solder Sn/Pb 63/37



Mag = 10.00 K X 1 μ m EHT = 15.00 kV WD = 3 mm Signal A = InLens

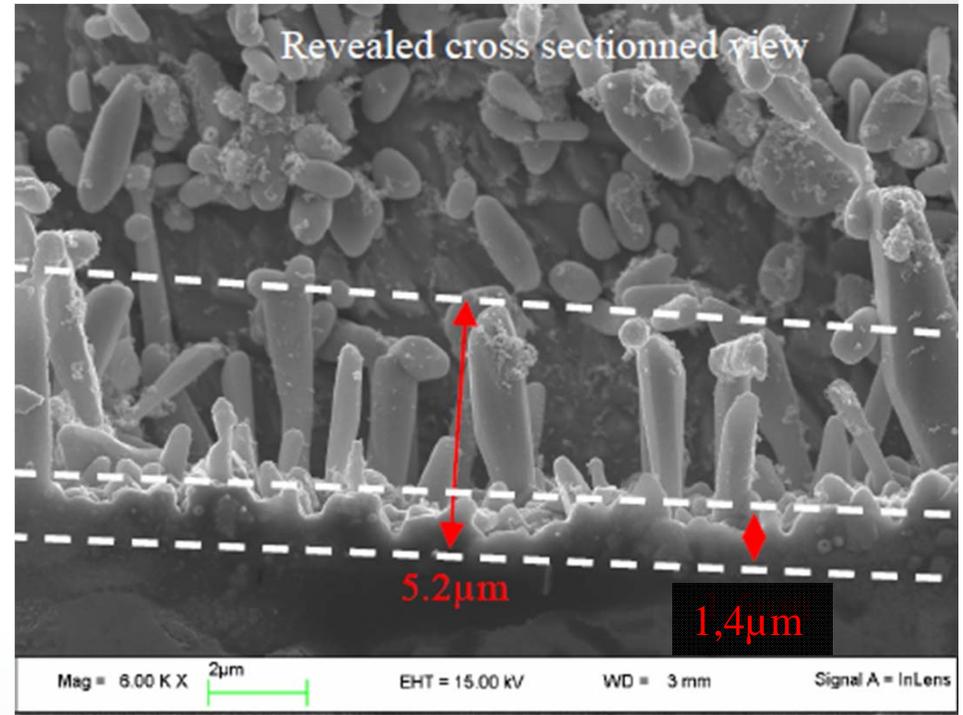
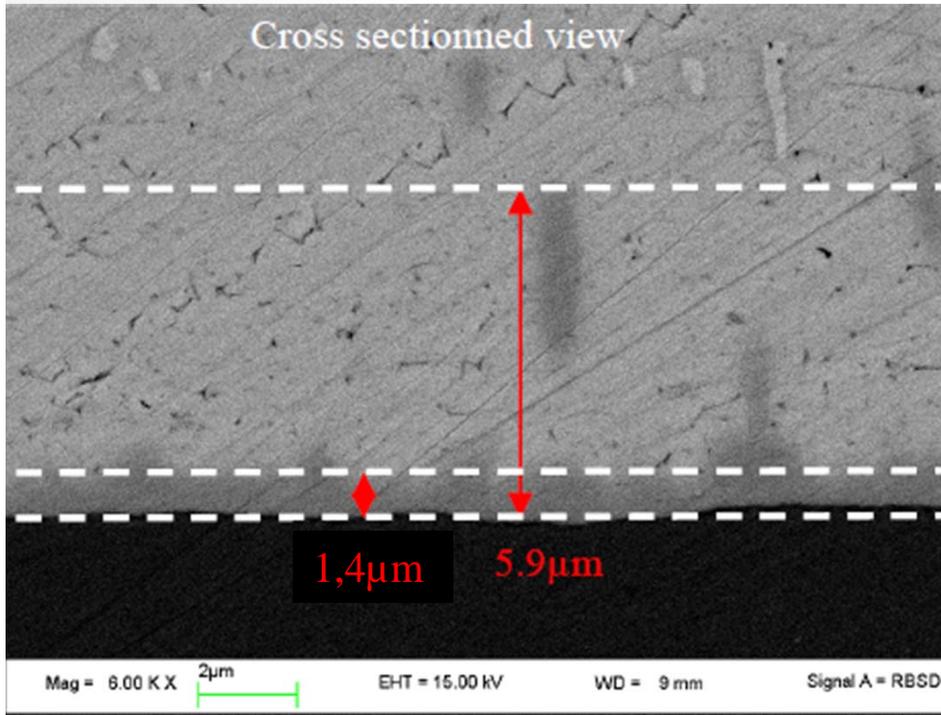
Lead Free: SAC305



Mag = 10.00 K X 2 μ m EHT = 15.00 kV WD = 3 mm Signal A = InLens

Finer structure in SAC, with larger specific surface \rightarrow better adherence IMC/solder, and then limited the risk of cracking.

IMC Size measurement on SAC



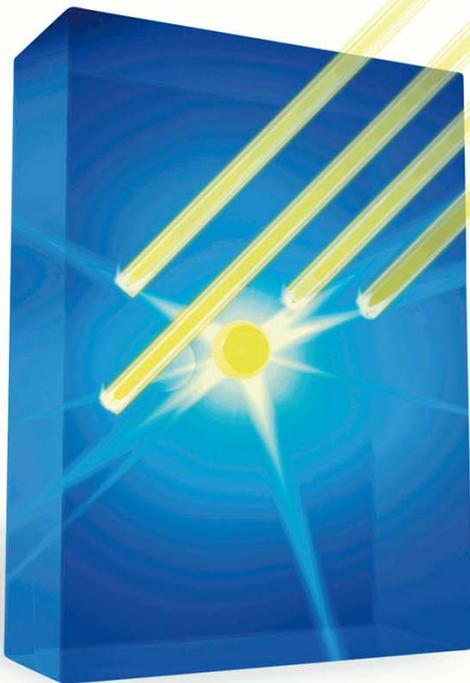
Results	Leaded Sn/Pb 63/37 Bath	Lead free SAC 305 Bath
IMC Thicknesses	Min (T0): 0,46 μm , Max (T1000): 1,47 μm	Min (T0): 0,74 μm Max (T1000): 1,36 μm
Morphology	@T0: 2 phases, fine structures @T500 and T1000: 1 phase, coarse structure	Fine structure whatever the ageing time
Formation/growth conditions	Large effect of isothermal ageing Low influence of process parameters (Time and Temperature)	Large effect of isothermal ageing Influence of soldering time
Comments	Measurement method in 2D representative	Measurement method in 2D not completely representative

Conclusion & Next Steps

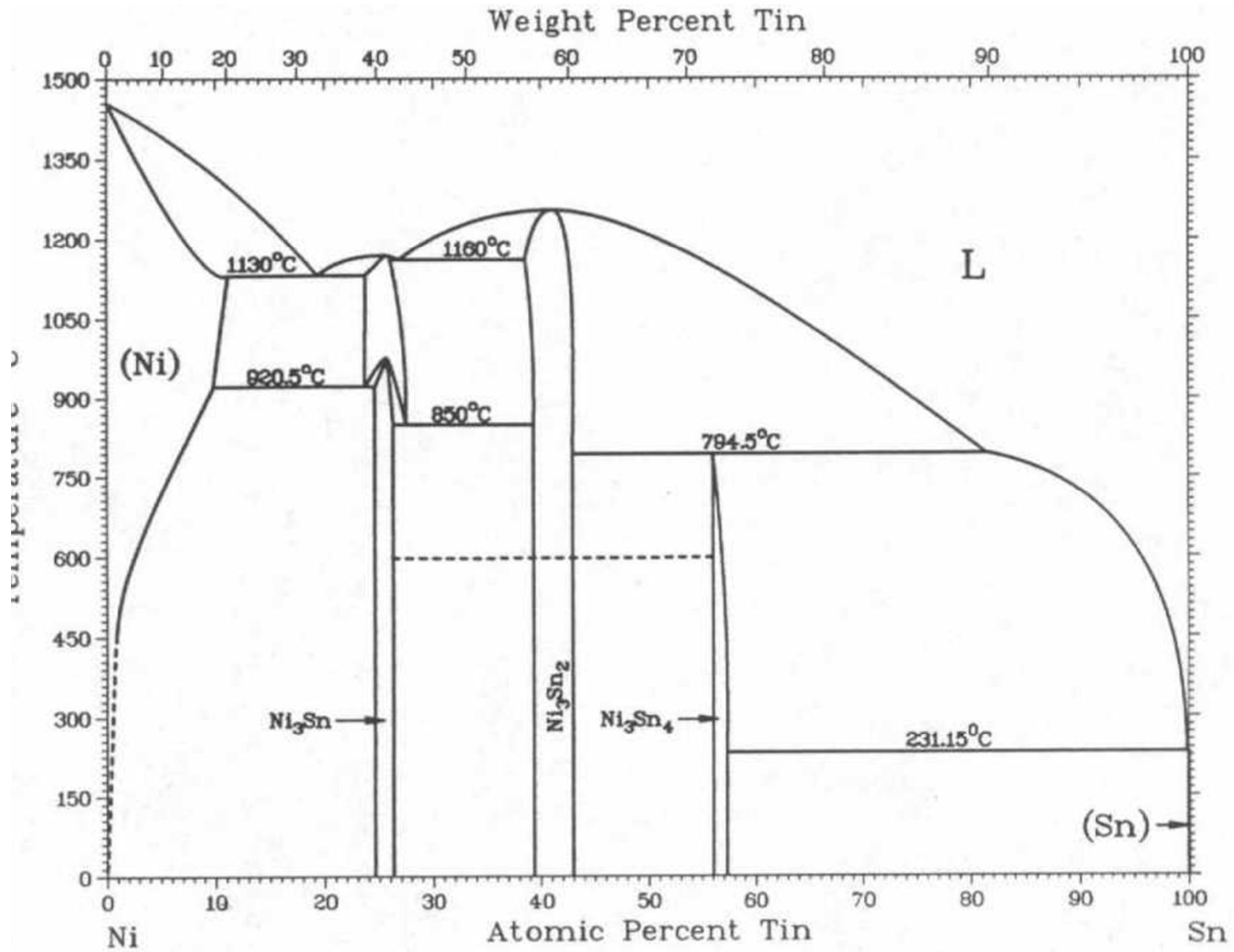
- Thickness measurements: necessary, but not sufficient on SAC305
- Different morphologies at T0 and in ageing
- SAC 305 IMC size more sensitive to Process parameters (solder time)

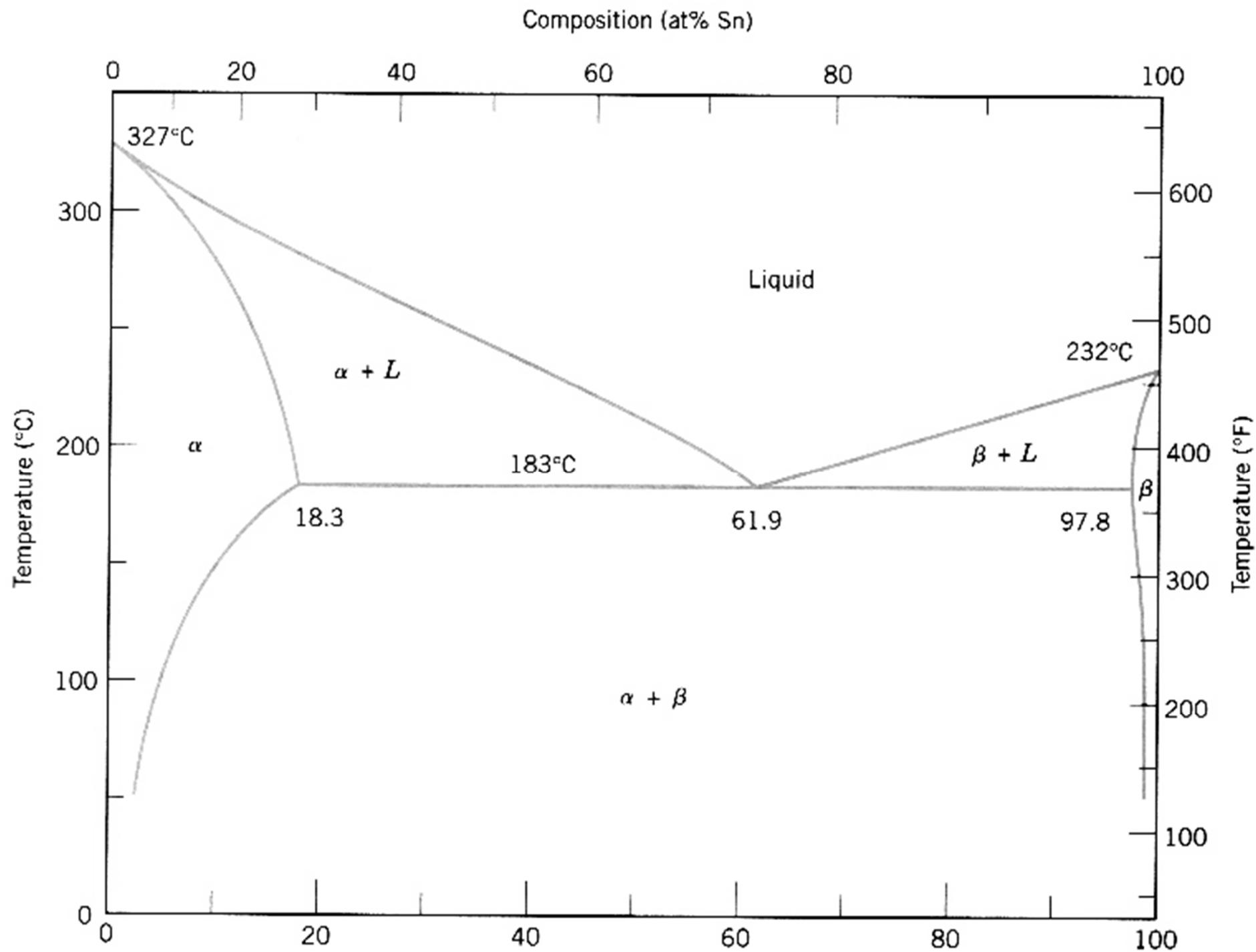
Next steps: Check the effects of other parameters:

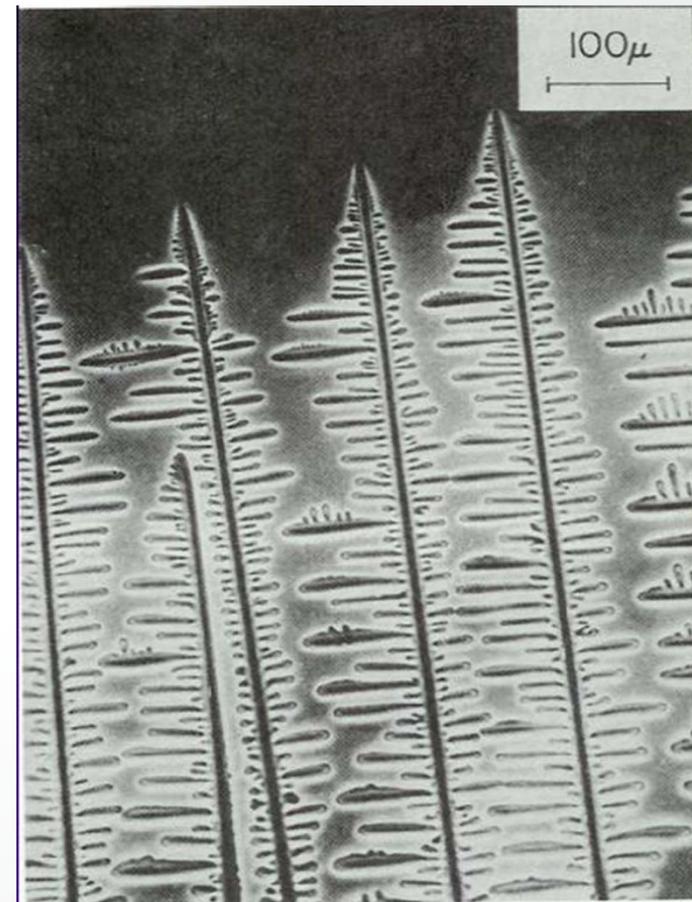
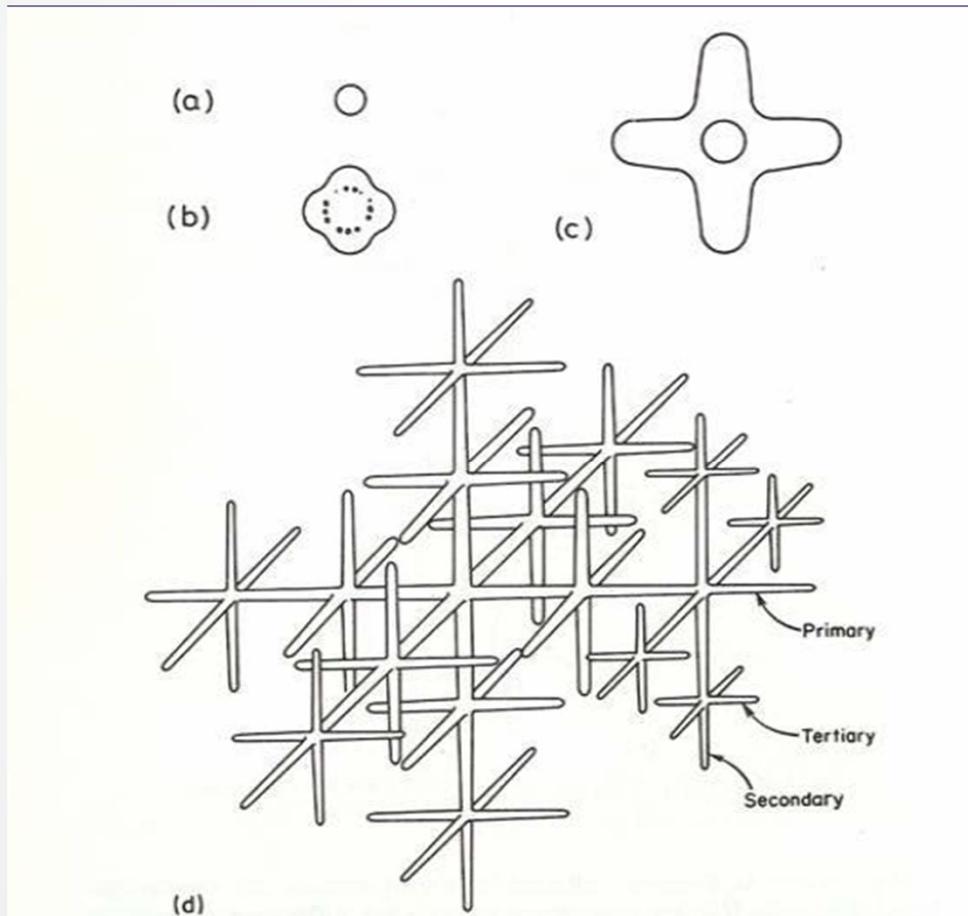
- Reflow, with temperature profil
- Isothermal temperature
- Other ageing ways (rapid temperature change, cycles...)
- Shape factors (components, vias, leads etc...)
- Other solder alloys
- Power supply
- Cross check morphological observations to mechanical properties (pull test...) and to reliability levels to specific sollicitations
- Other finishing Silver, OSP, ENEPIG (Au/Pd/Ni)



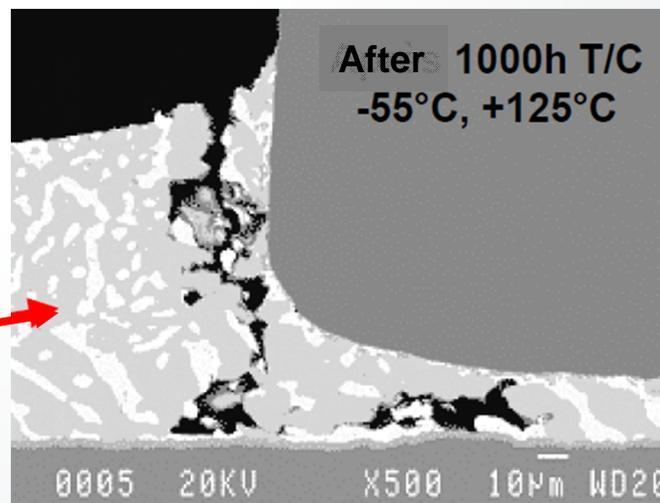
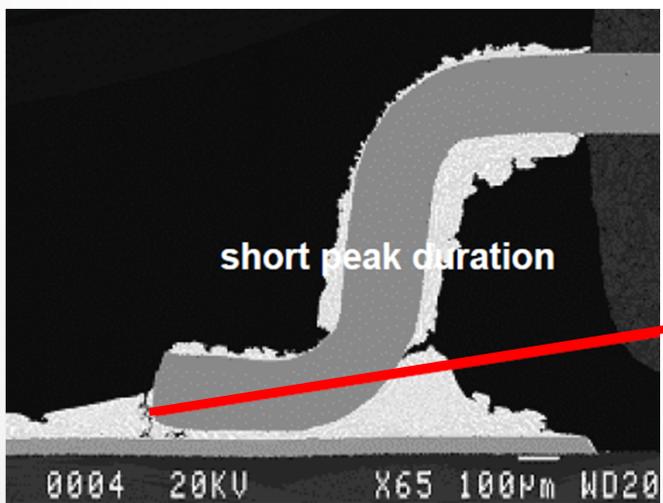
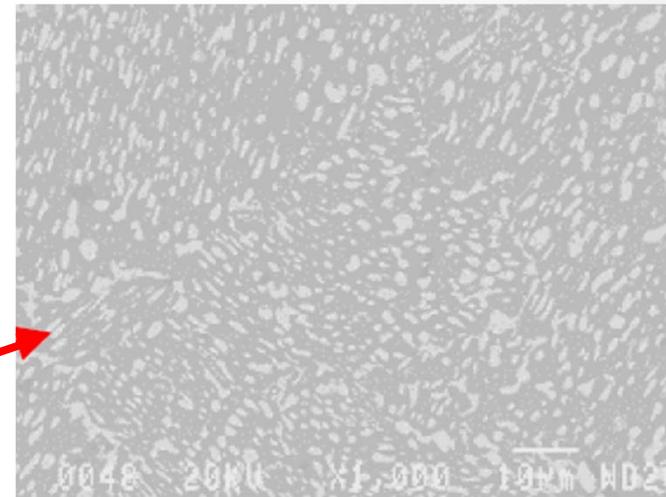
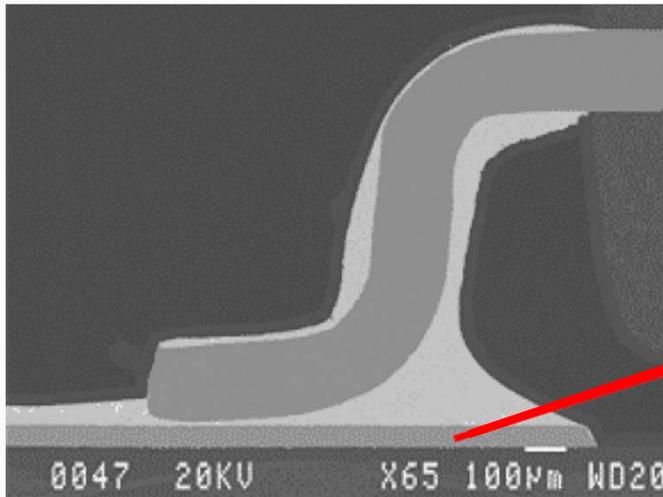
*Thanks for your attention
Questions?*

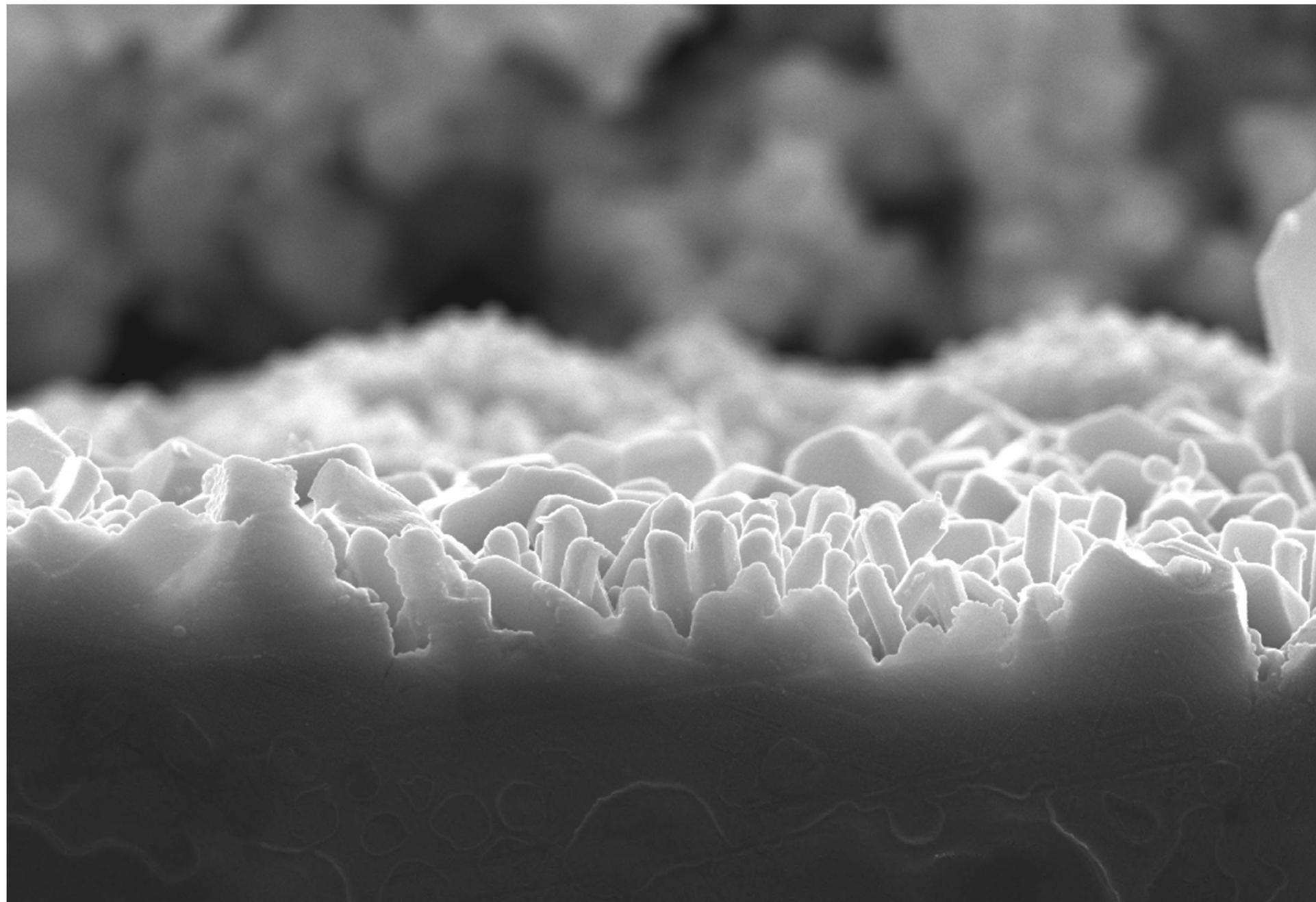






Phase coarsening





Mag = 15.00 K X

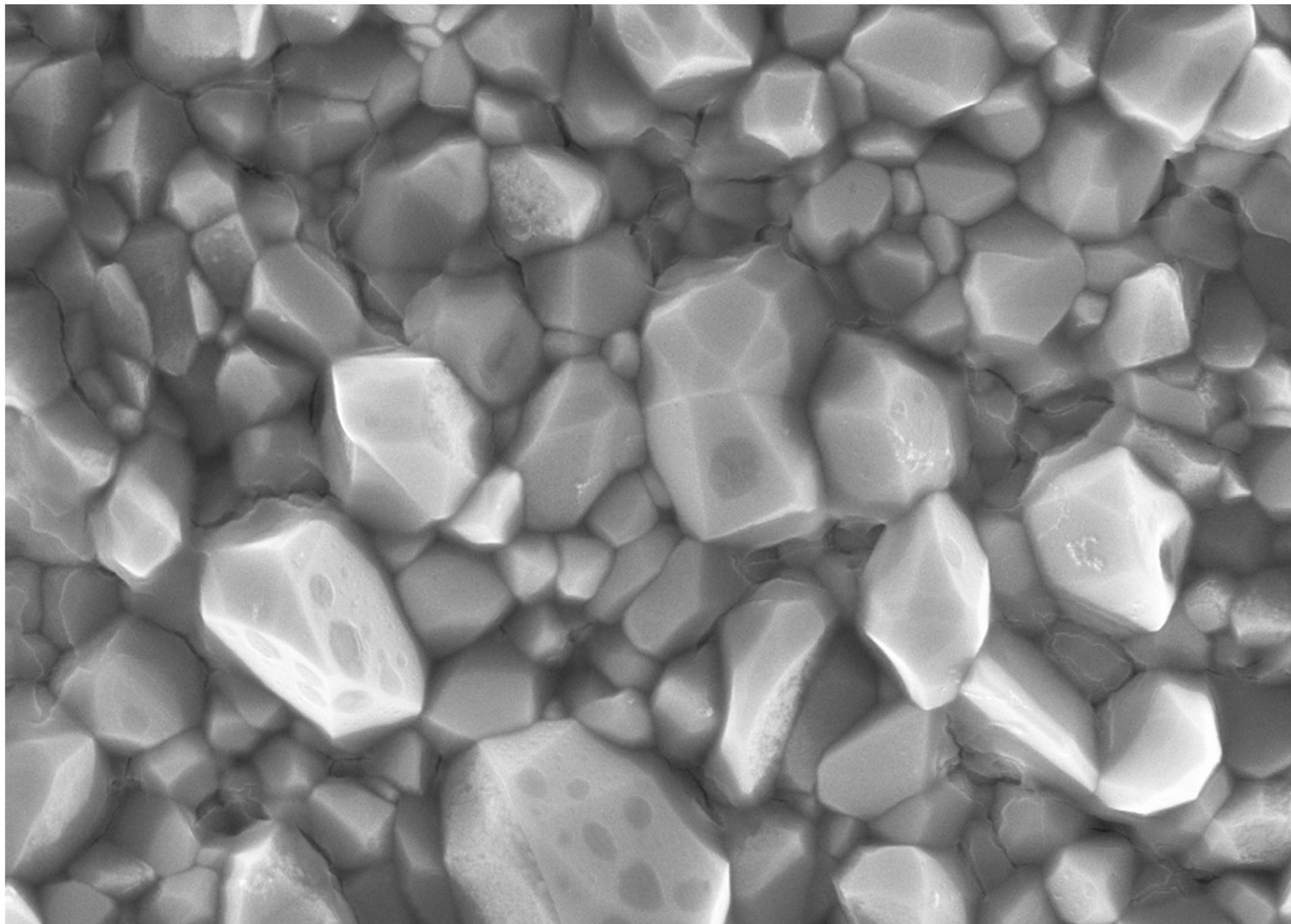
1 μ m



EHT = 15.00 kV

WD = 3 mm

Signal A = InLens



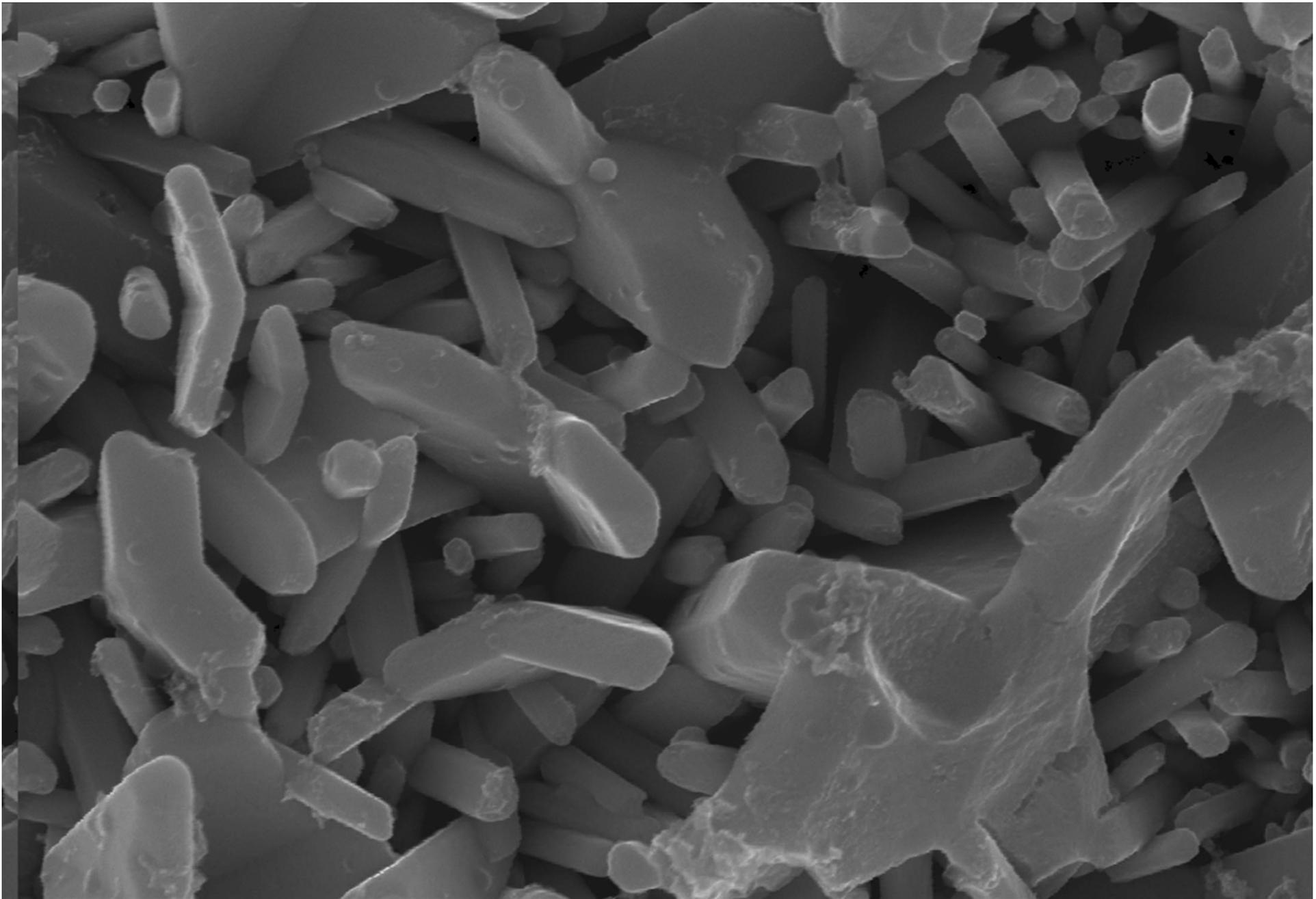
Mag = 10.00 K X

1 μm

EHT = 15.00 kV

WD = 3.9 mm

Signal A = InLens



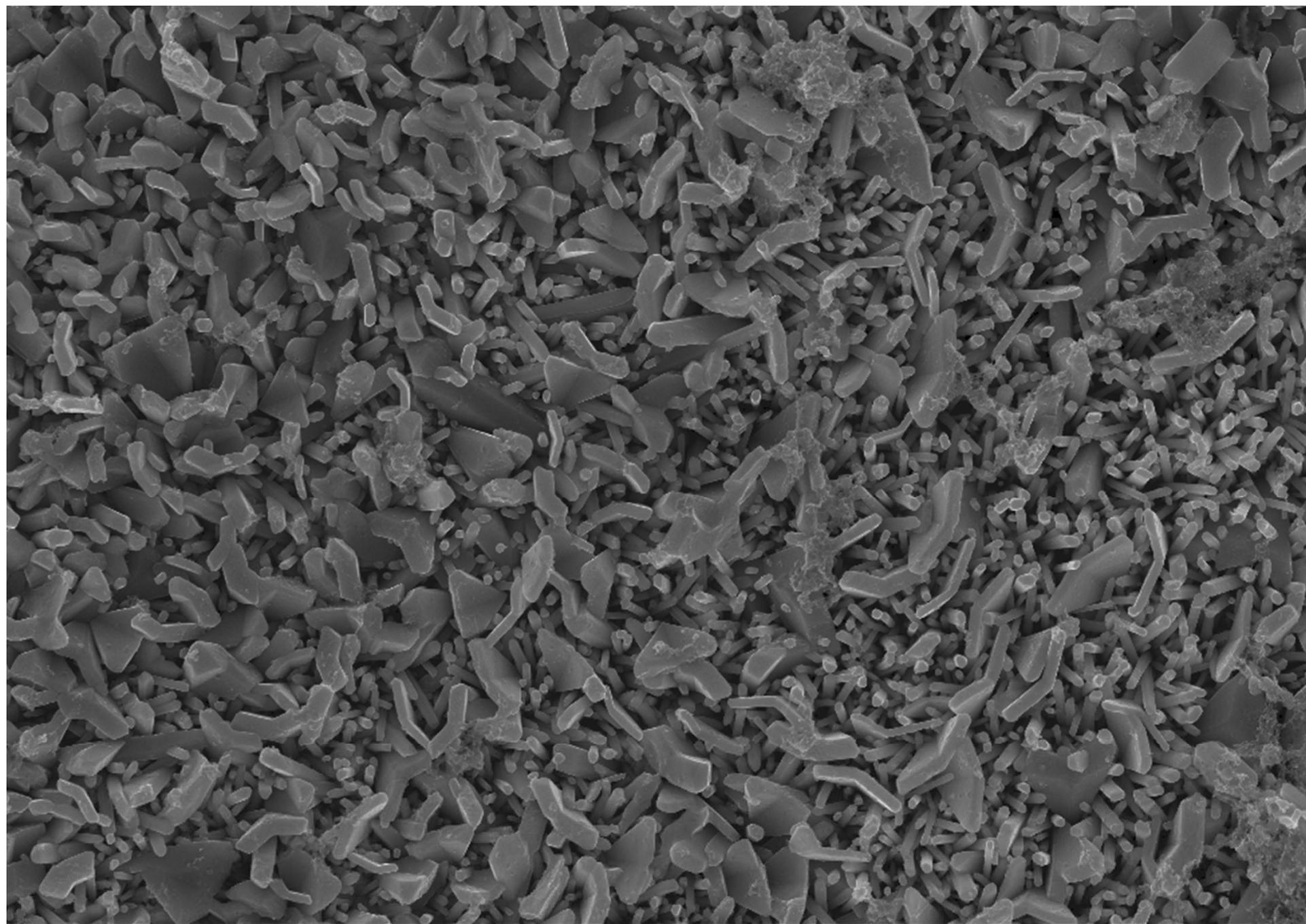
Mag = 30.00 K X



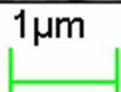
EHT = 15.00 kV

WD = 3 mm

Signal A = InLens



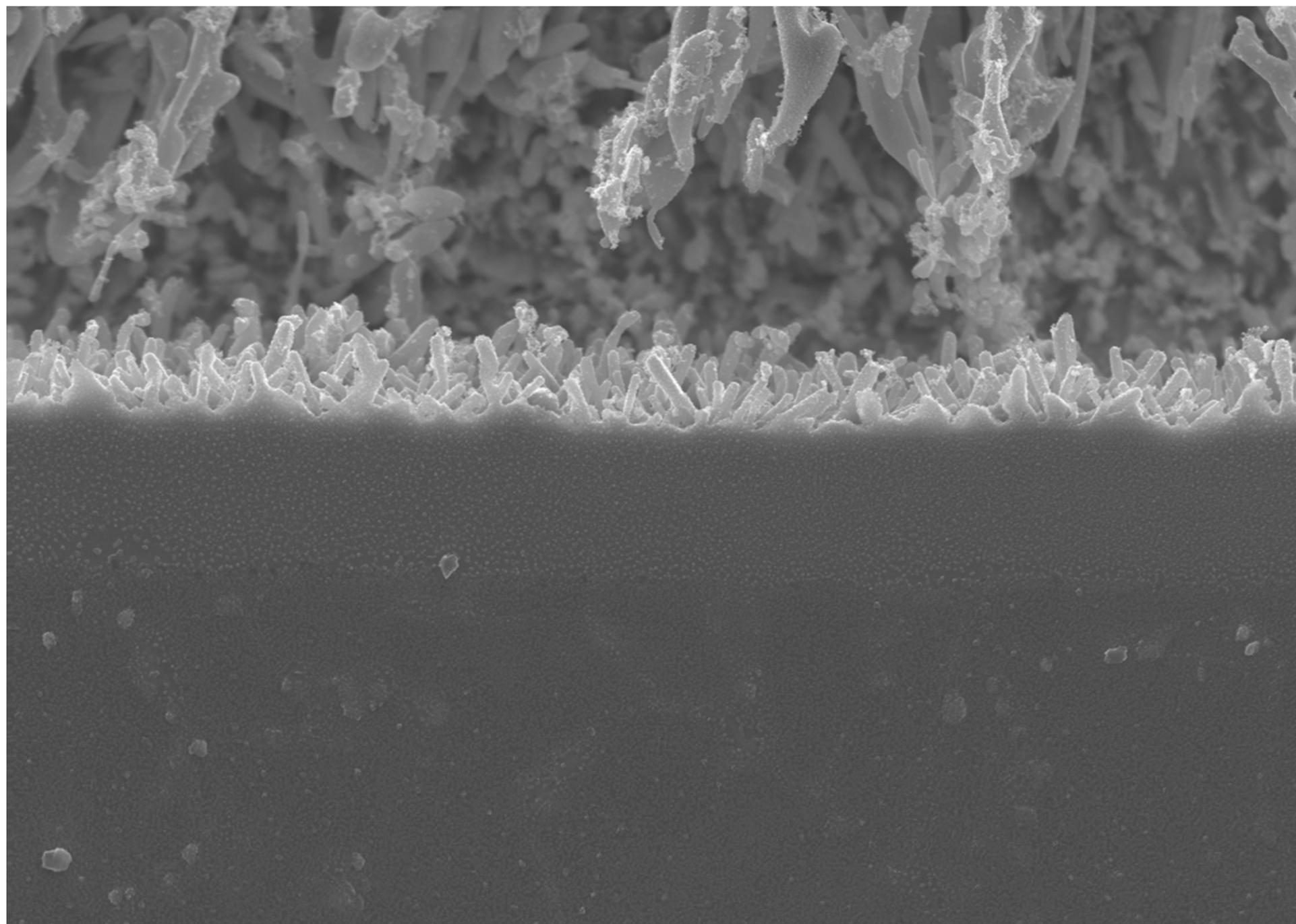
Mag = 6.00 K X



EHT = 15.00 kV

WD = 3 mm

Signal A = InLens



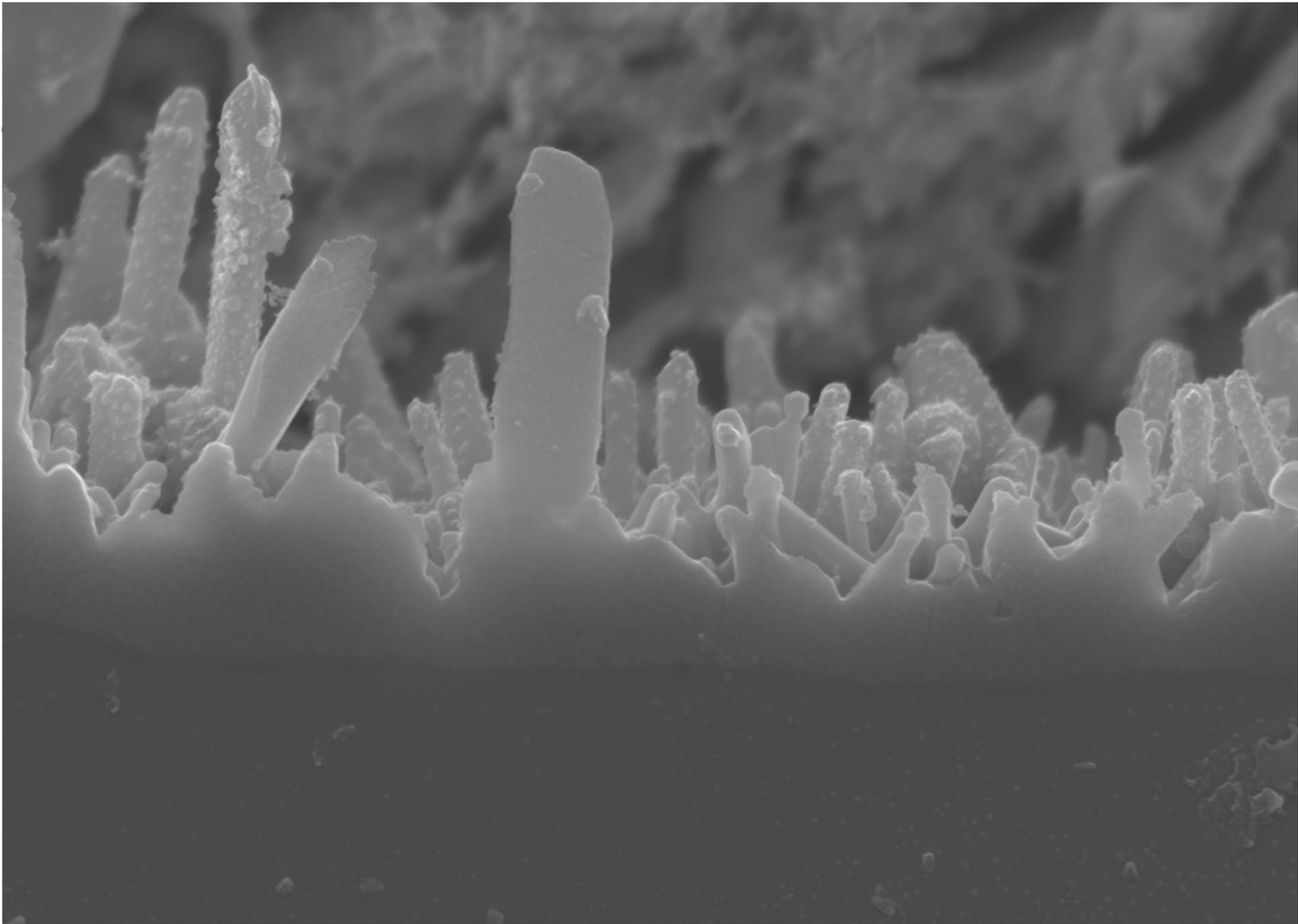
Mag = 3.00 K X

2 μ m

EHT = 20.00 kV

WD = 2.7 mm

Signal A = InLens



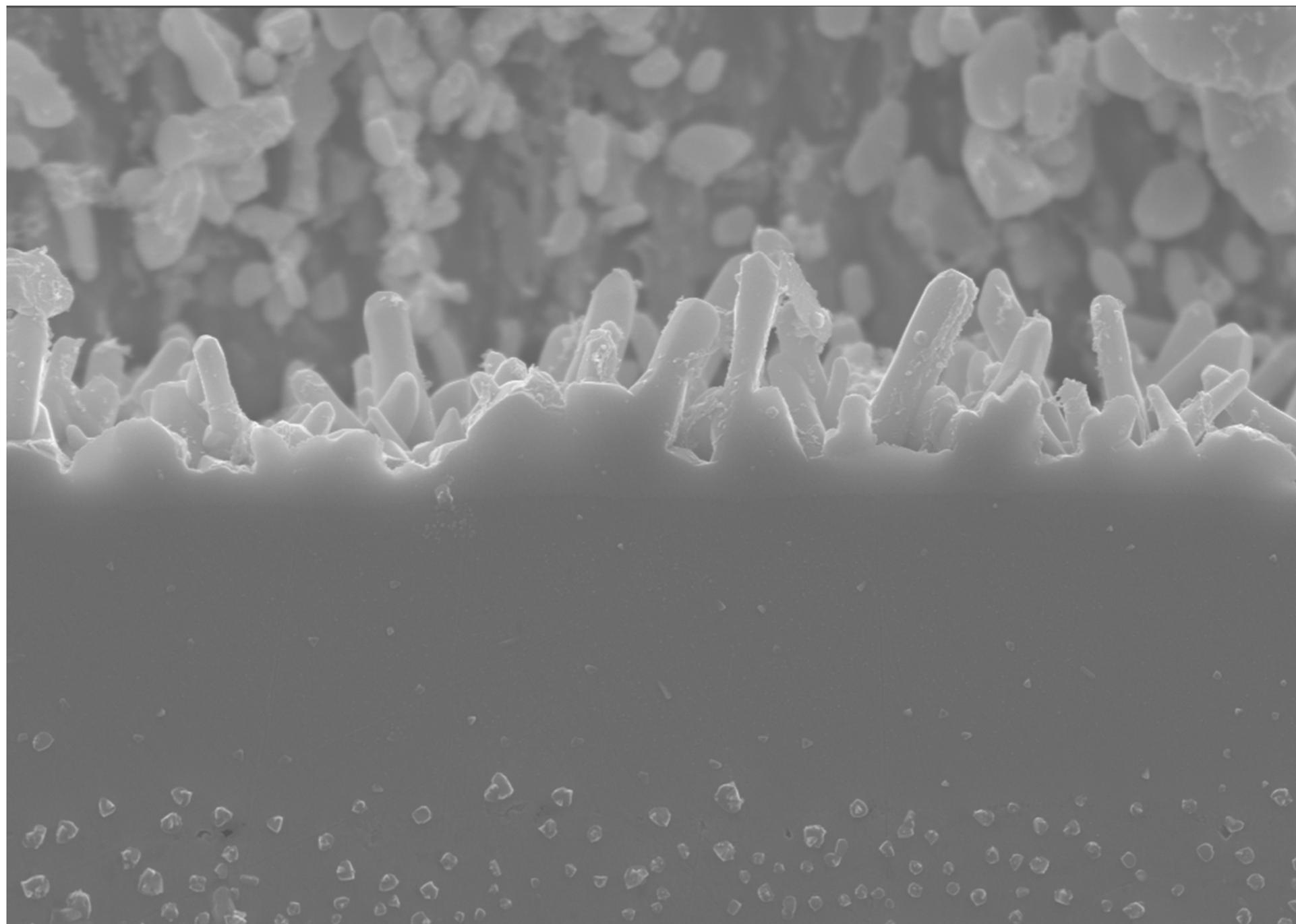
Mag = 10.00 K X

2 μm

EHT = 20.00 kV

WD = 2.7 mm

Signal A = InLens



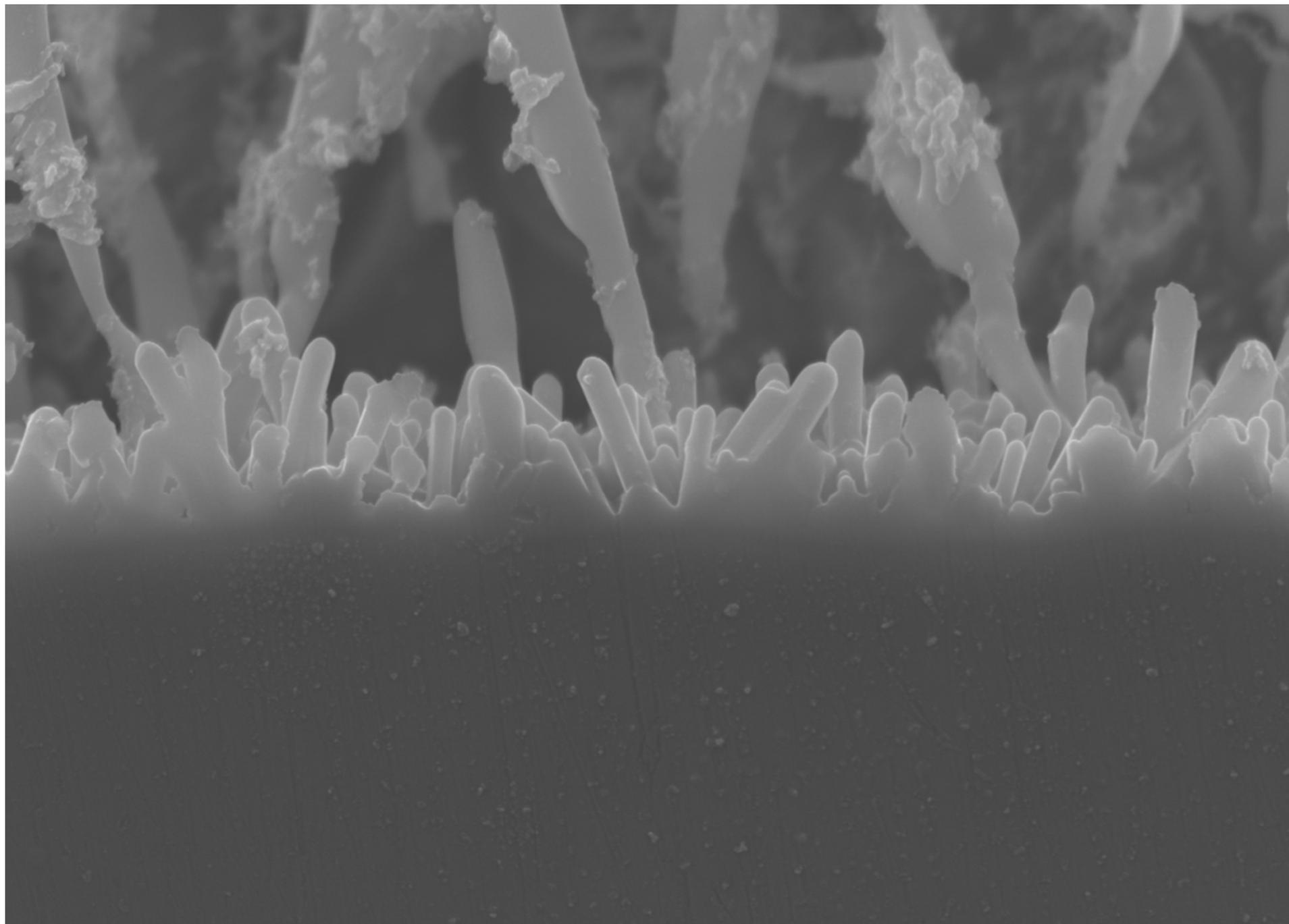
Mag = 6.00 K X

2 μ m

EHT = 20.00 kV

WD = 2.9 mm

Signal A = InLens



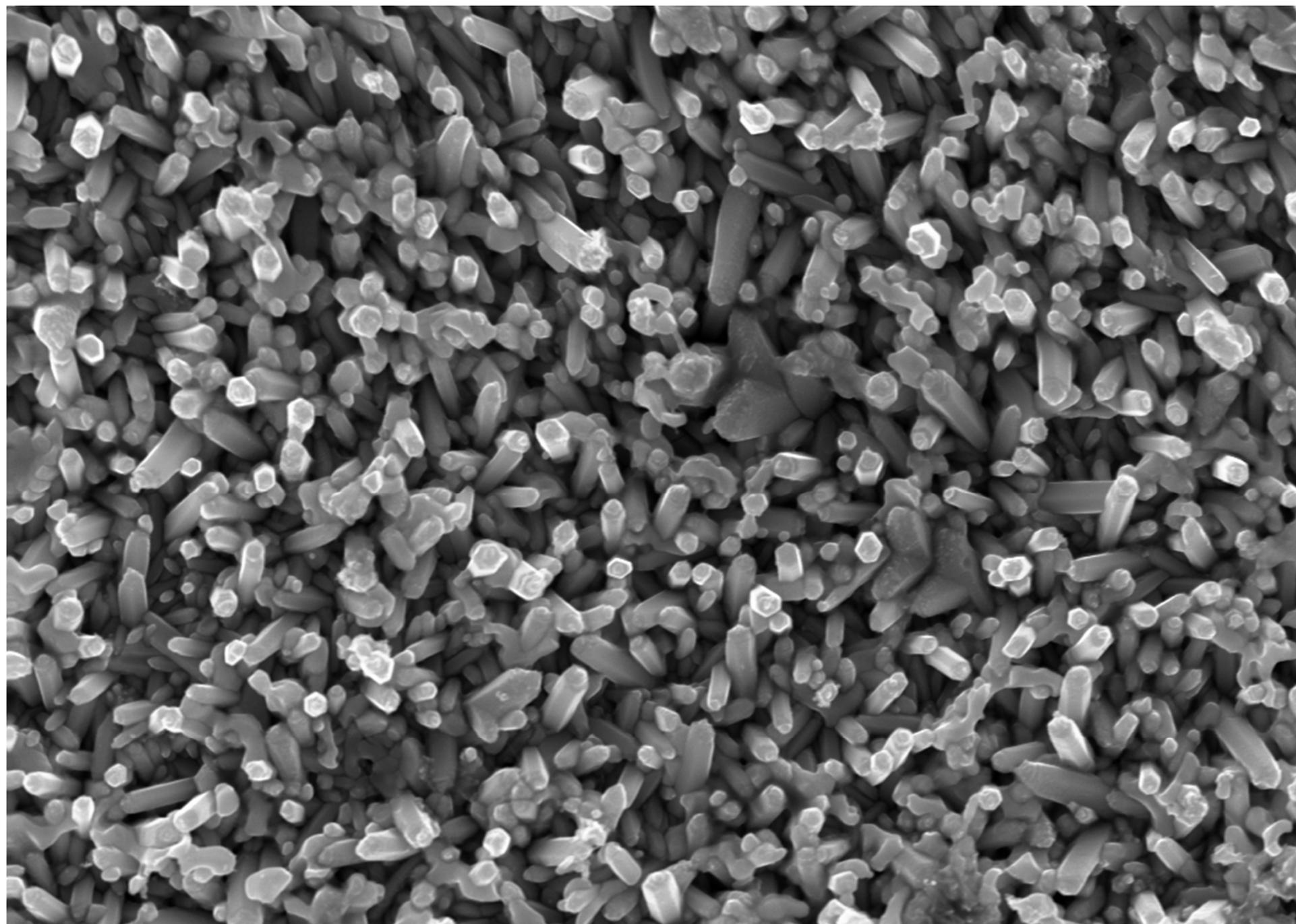
Mag = 10.00 K X

2 μ m

EHT = 20.00 kV

WD = 2.5 mm

Signal A = InLens



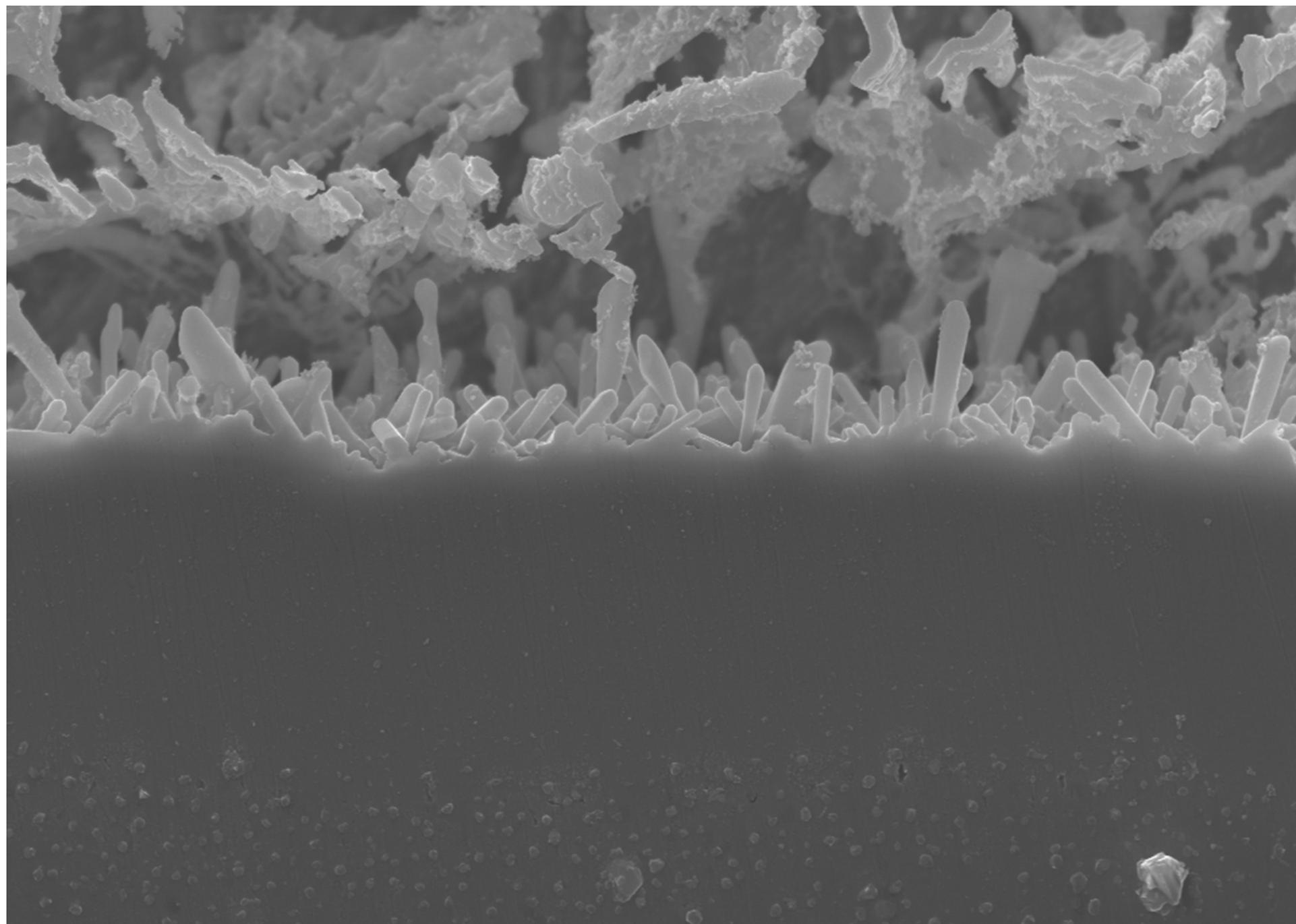
Mag = 10.00 K X

2 μ m

EHT = 15.00 kV

WD = 3.7 mm

Signal A = InLens



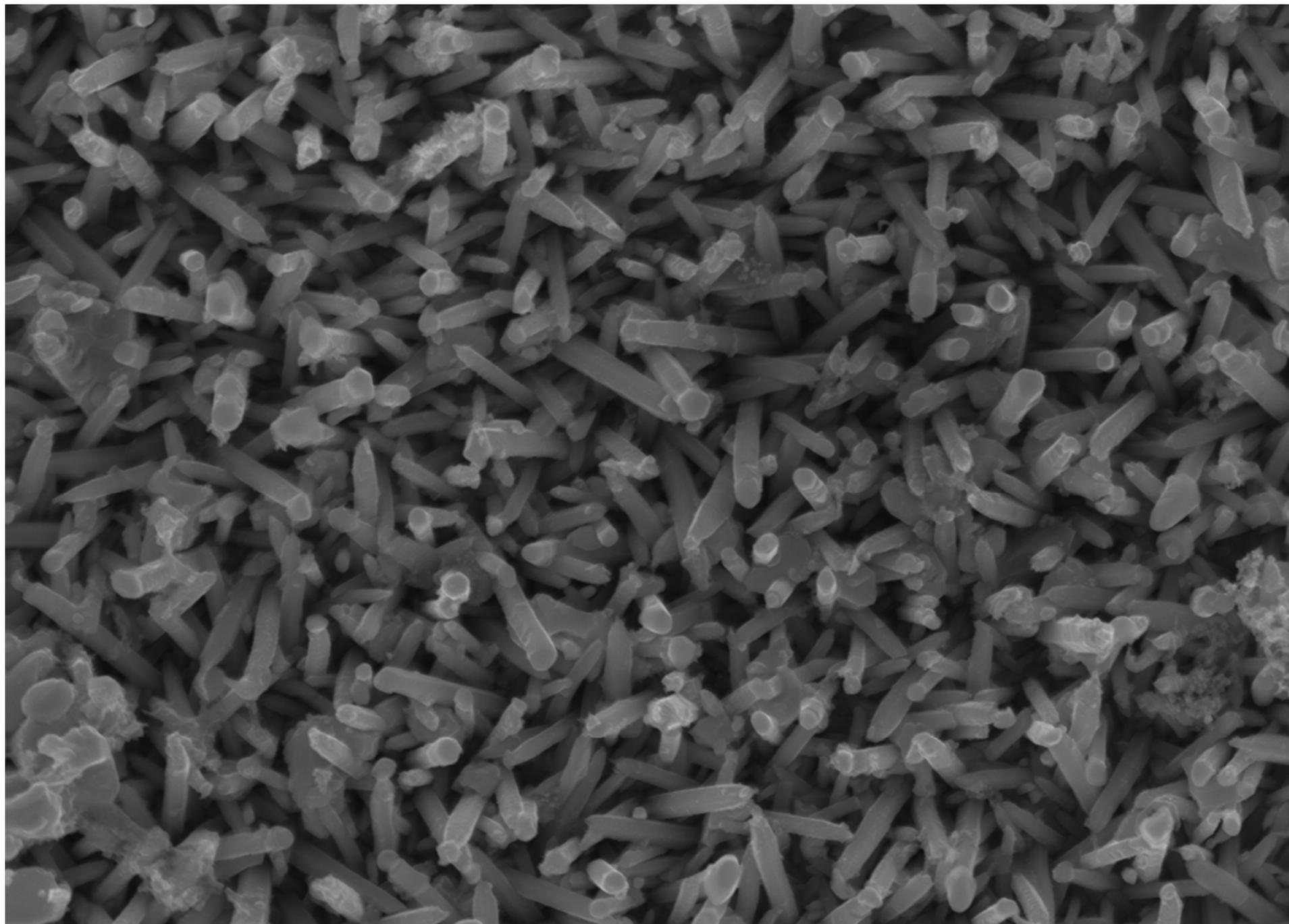
Mag = 6.00 K X

2 μ m

EHT = 20.00 kV

WD = 2.5 mm

Signal A = InLens



Mag = 10.00 K X

2 μ m

EHT = 15.00 kV

WD = 2.8 mm

Signal A = InLens